

高分解能広立体角2次元光電子顕微分光器 (DELMA)の開発

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酒井智香子^a, 北川 哲^a、森田 誠^a、大門 寛^a

^a奈良先端科学技術大学院大学 (NAIST), ^bDebrecen大学, ^cJASRI-SPring-8



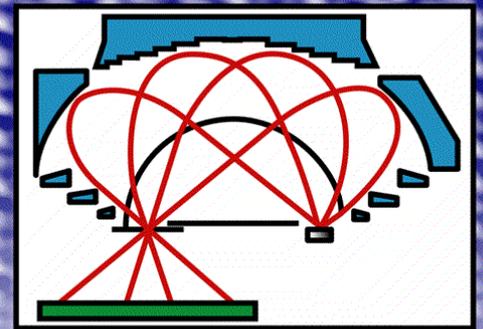
松田巖、
山本達
(ISSP)

Outline

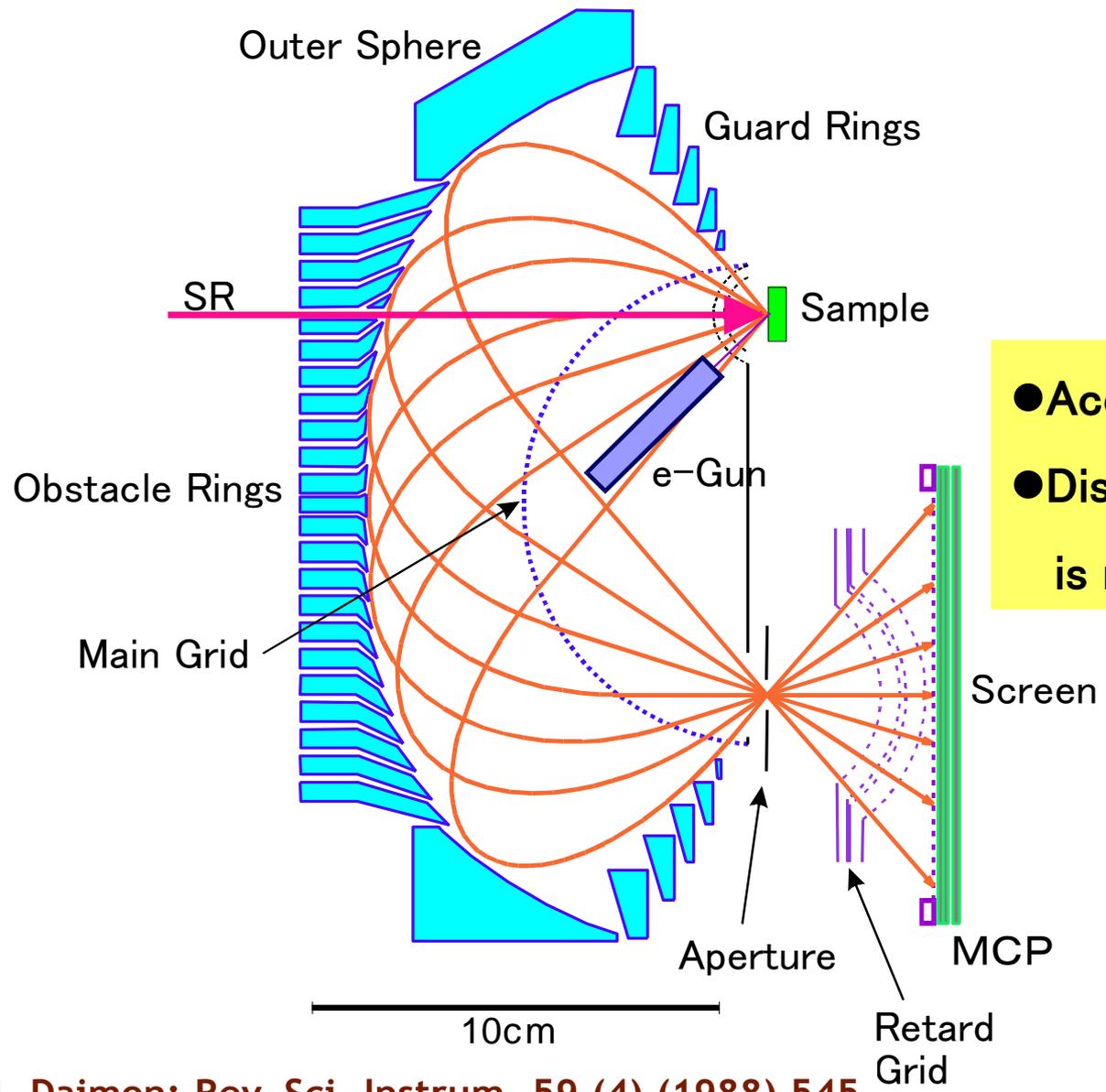
- Conventional Two-dimensional photoelectron spectrometer (DIANA)
- New Photoelectron Emission Microscope for Stereophotography (DELMA)
- Application to graphene

科研費 基盤(S) (20224007)

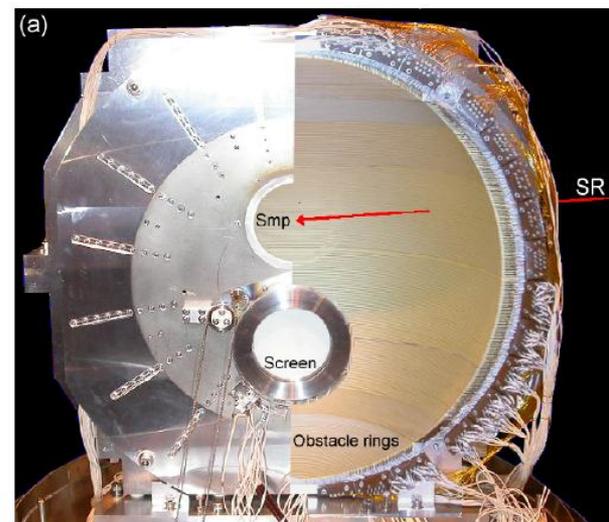
Two-dimensional photoelectron spectrometer Display-type Spherical Mirror Analyzer (DIANA)



Surface and Materials
Science Laboratory



- Acceptance angle $\pm 60^\circ$
- Displayed angular distribution is not distorted



Rits BL-7: LP-VUV 2D-ARPES Beam line

BL-7(Rits-SR center):

35 ~ 130 eV

Linearly Polarized light

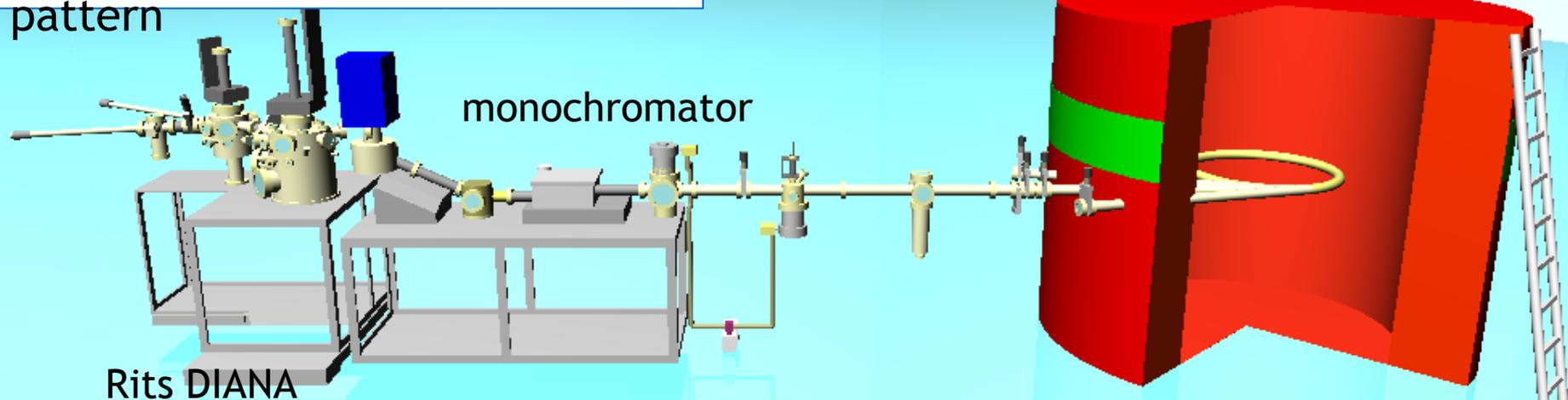
Analyzer:

total resolution $\Delta E / E \sim 1\%$

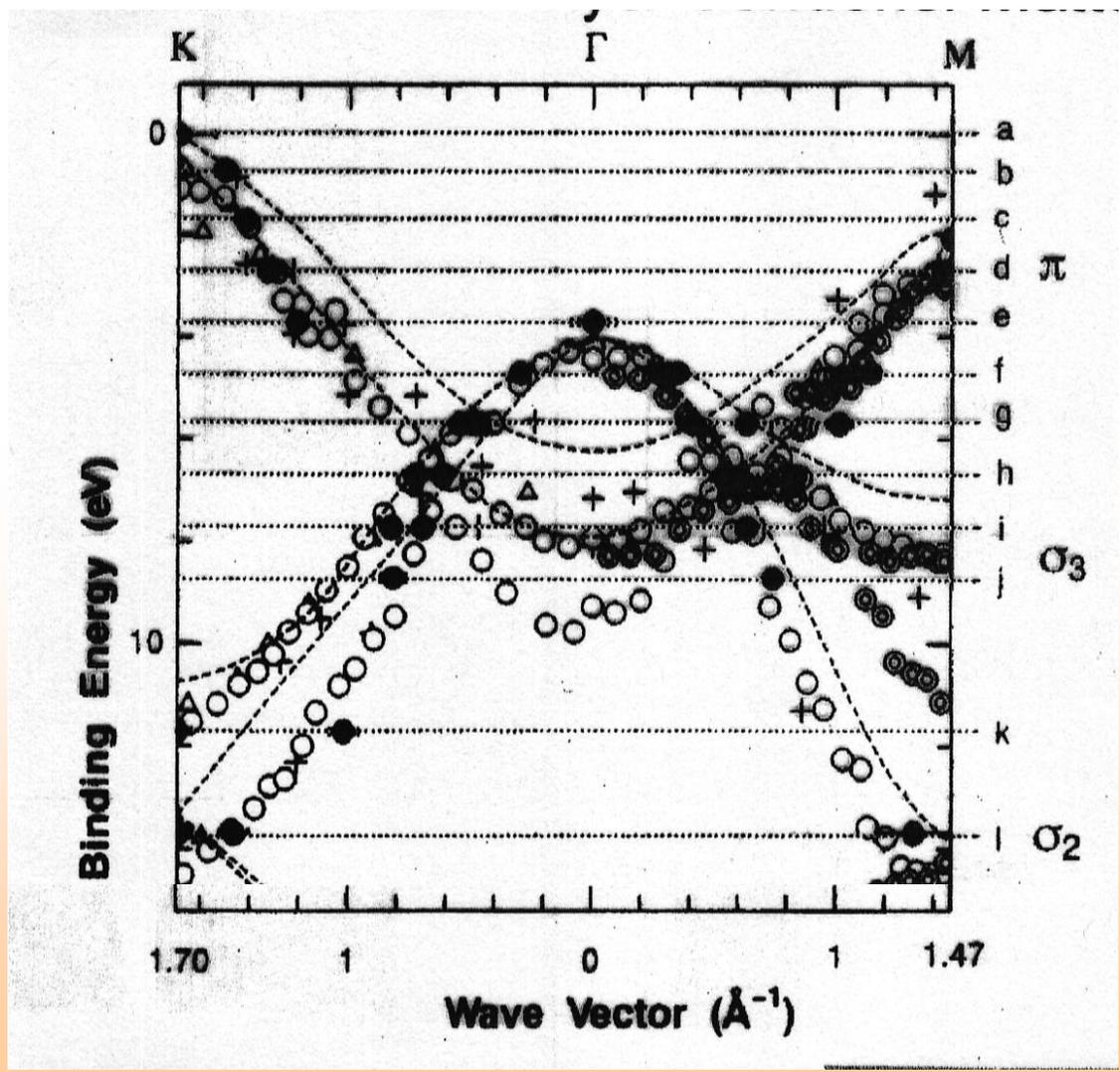
angular resolution $\pm 0.5^\circ$

acceptance angle $\pm 50^\circ$

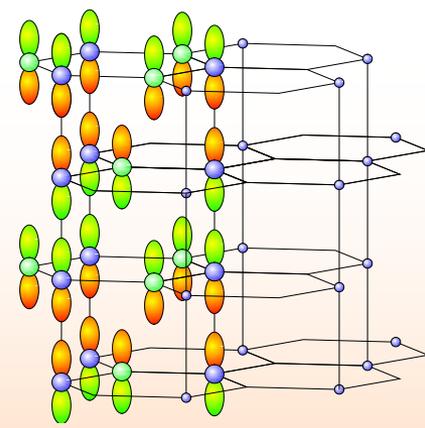
acquisition time ~ 5 min /
pattern



π band dispersion of graphite in k_z direction

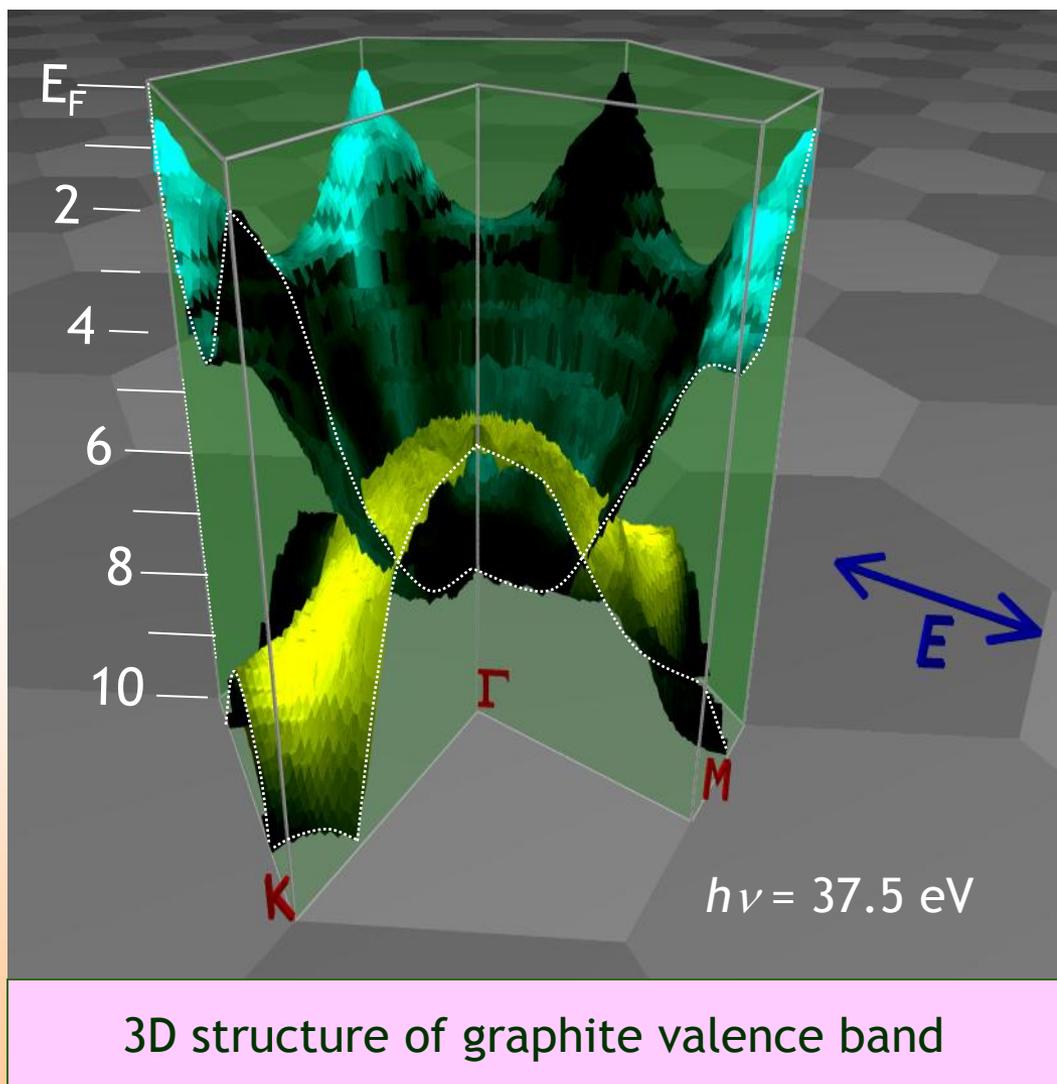
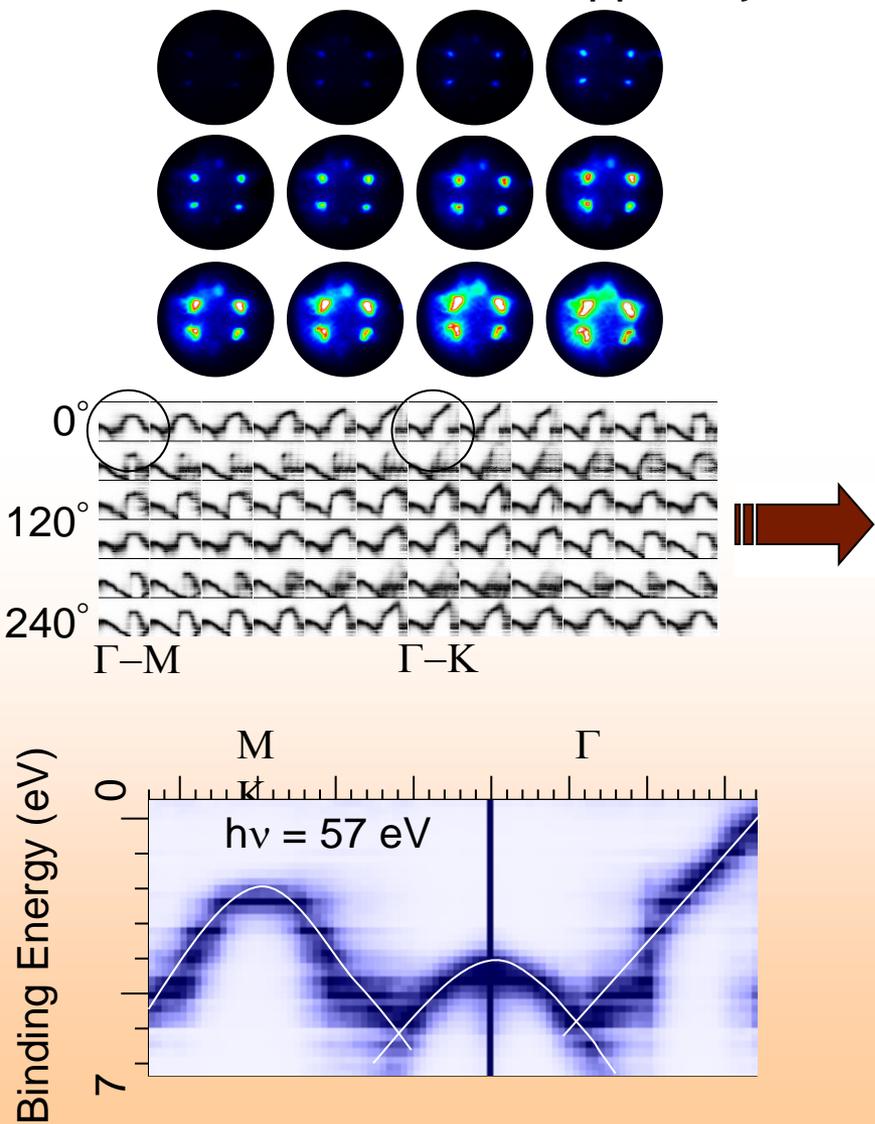


π bonding band

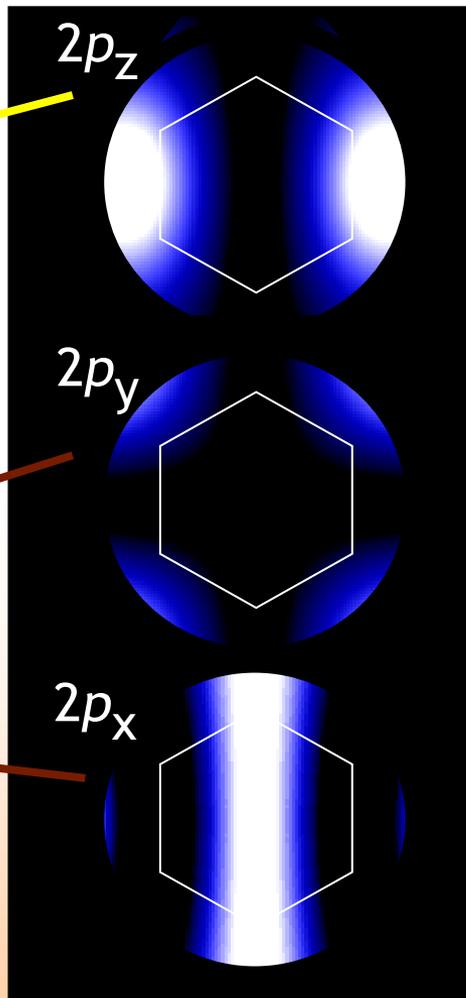
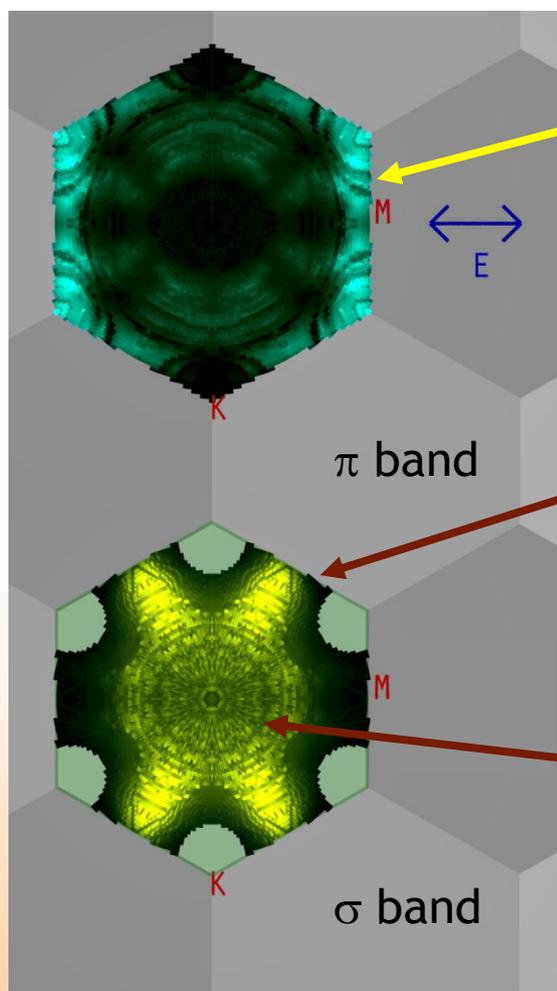


Three Dimensional Valence Band Dispersion

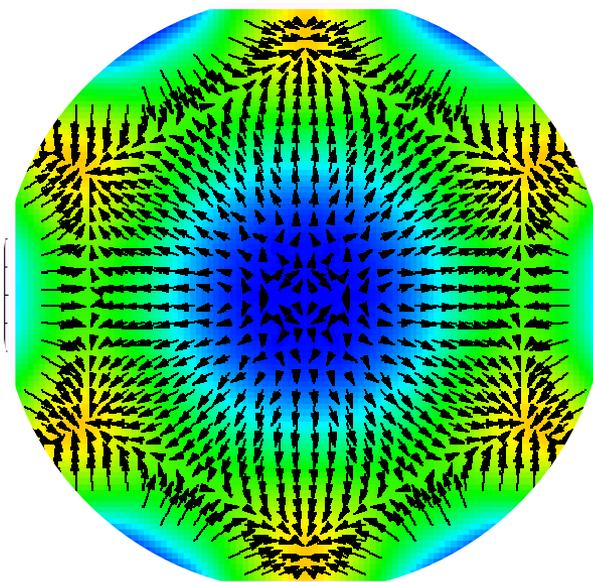
F. Matsui, Y. Hori, H. Miyatake, N. Suganuma, H. Daimon, H. Totsuka, K. Ogawa, T. Furukubo, H. Namba: Appl. Phys. Lett. 81 (2002) 2556.



Valence band dispersion of graphite

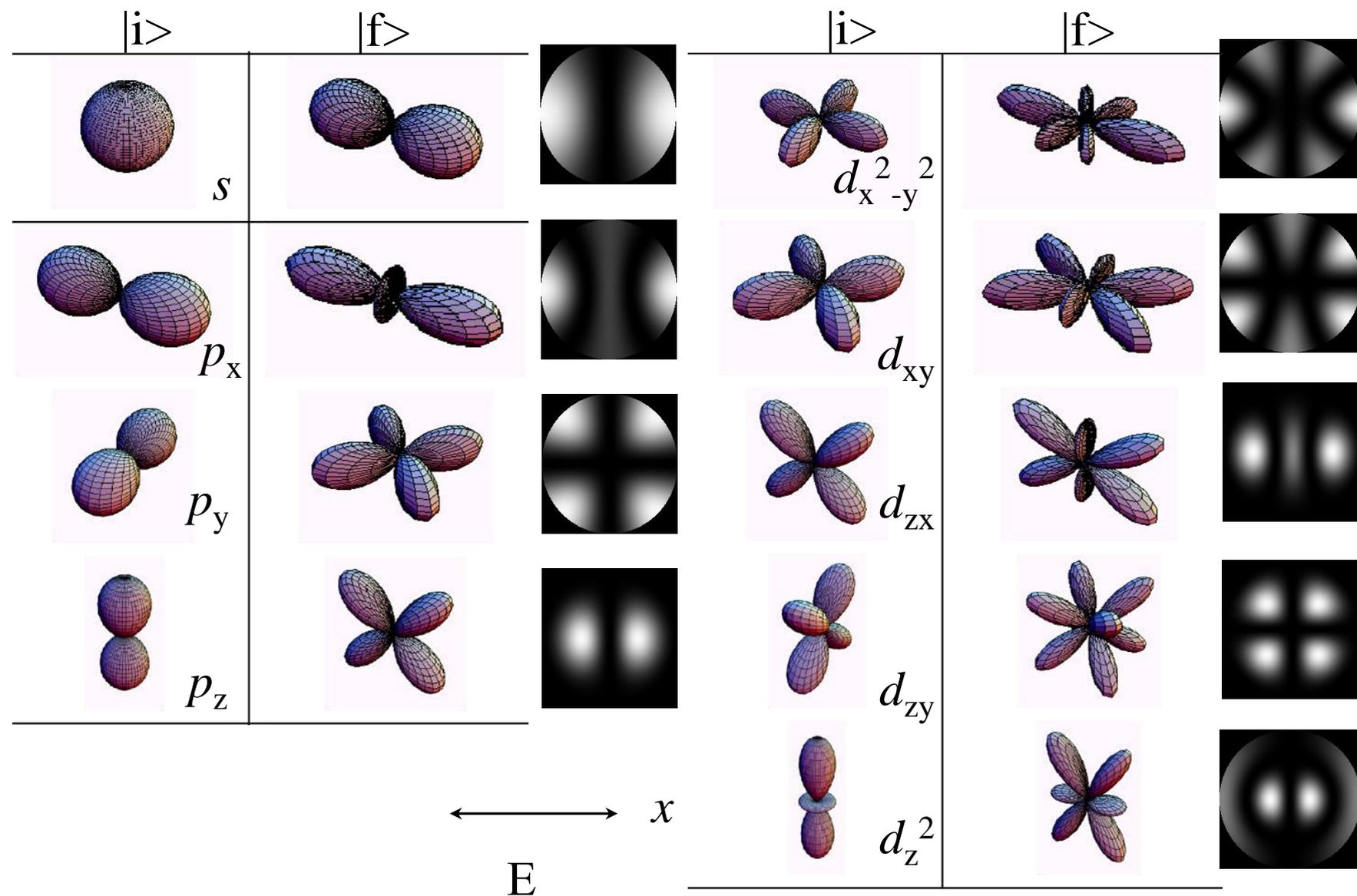


F. Matsui, et al., Appl. Phys. Lett. **81** (2002) 2556.



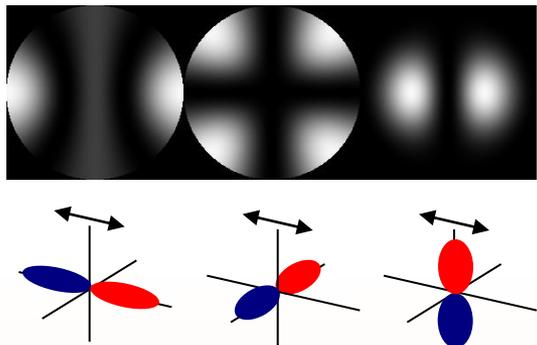
Differential of π band:
 Group velocity of electrons
 \propto differential of band dispersion

$$\mathbf{v}_g = 1/\hbar(d\varepsilon(\mathbf{k})/d\mathbf{k})$$

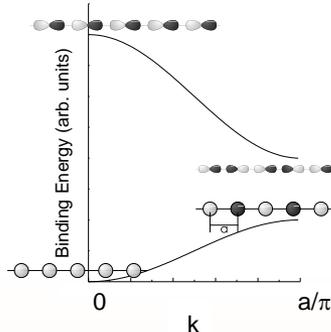


4 factors in photoelectron angular distribution

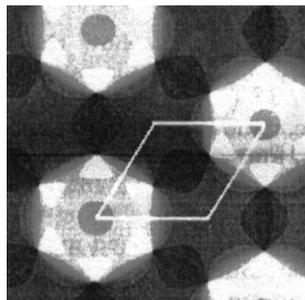
Angular distribution from atomic orbital



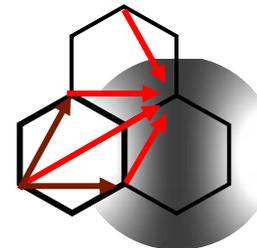
Dispersion of valence bands



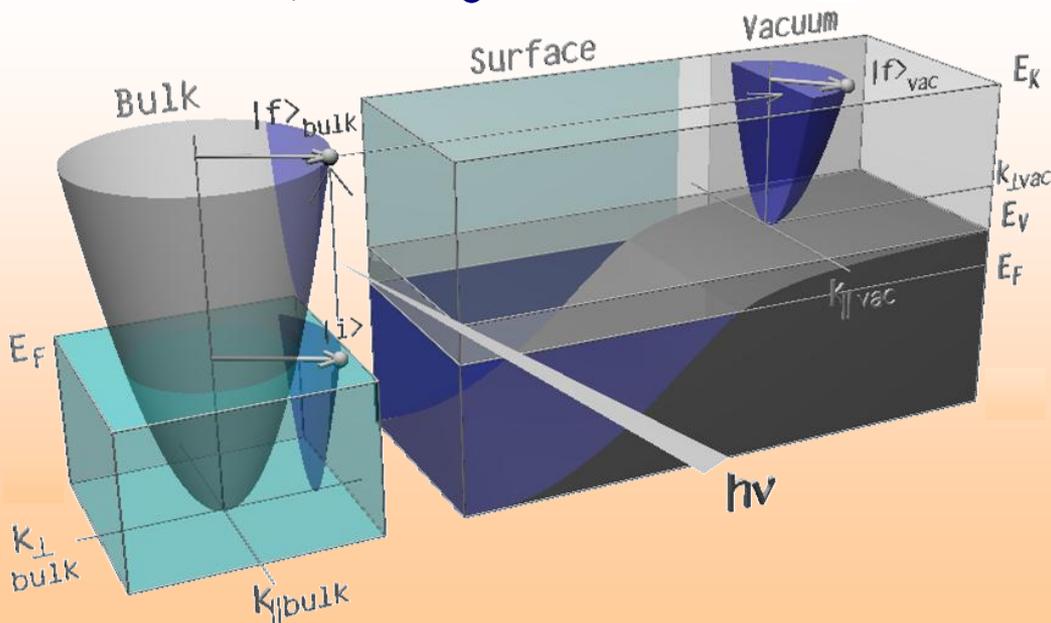
Structure factor of photoelectron



Final state effects



Umklapp process etc.



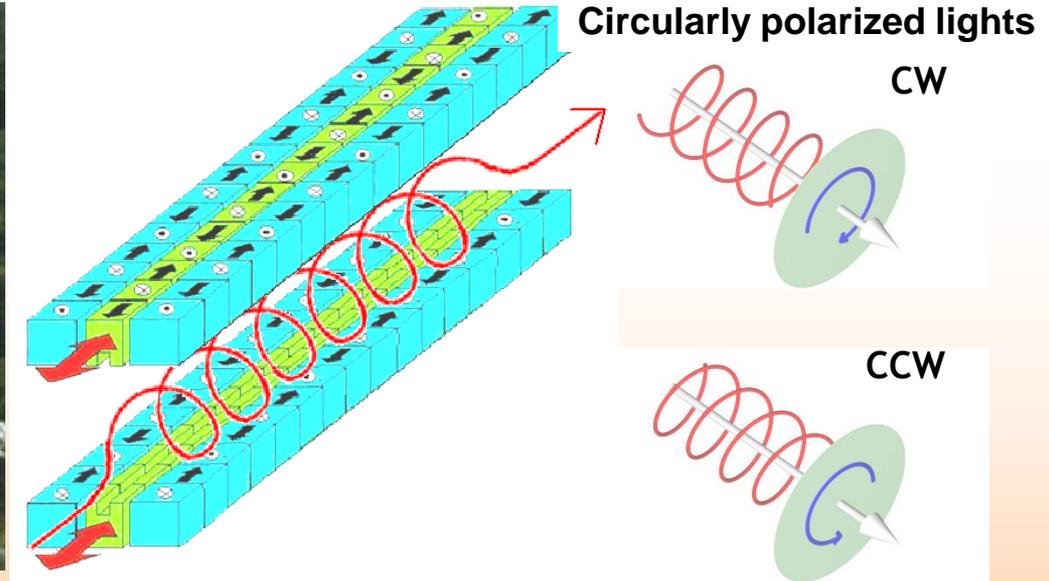
Binding energy scan:
valence band dispersion

Photon energy scan:
 k_z variation of isoenergy surface

circularly polarized light synchrotron radiation

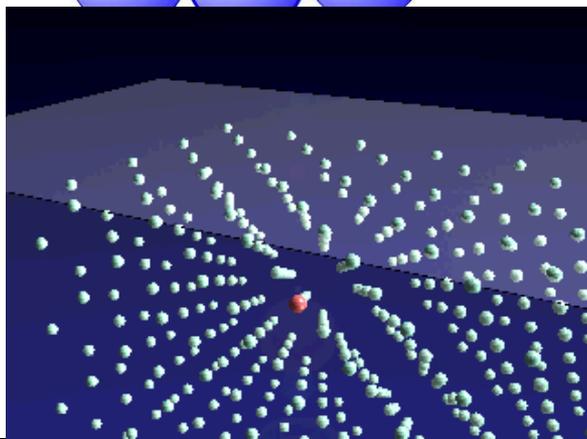
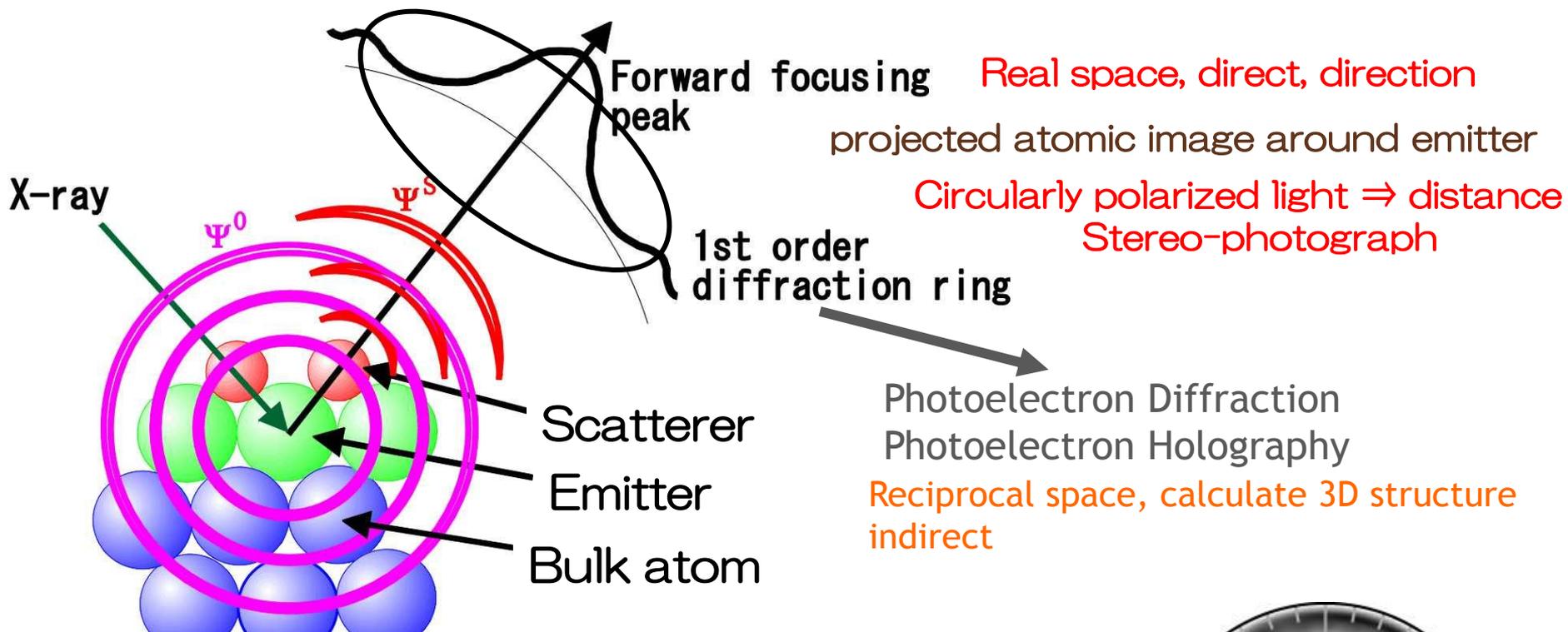


BL25SU (SPRING-8) with Twin helical undulators
($h\nu = 500 - 1500 \text{ eV}$)

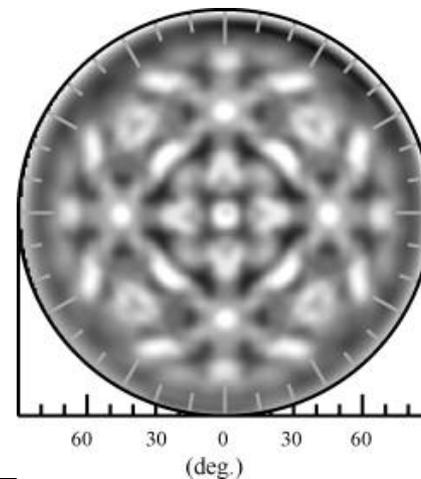


SPRING-8: the largest SR ring in the world.

Forward focusing peak (FFP) in Photoelectron Intensity Angular Distribution (PIAD)



Example of 2D-PIAD
Si2p from Si(001)



Initial m increases or decreases by 1
for ccw or cw light excited photoelectrons

CCW
 $m = m_i + 1$

CW
 $m = m_i - 1$

s : $l = 0$



Initial

$m_i = 0$

photoelectrons

CCW
 $m = 1$

d : $l = 2$



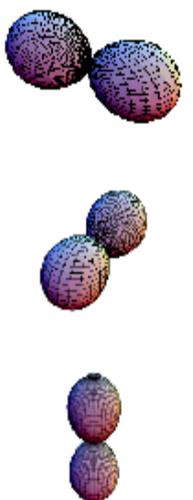
Initial

$m_i = \pm 2$

photoelectrons

CCW
 $m = 3$

p : $l = 1$



$m_i = \pm 1$

CCW
 $m = 2$

$m = 1$

$m_i = 0$

$m = 0$



$m_i = \pm 1$

$m = 2$

$m = 1$



$m = 0$



$m_i = 0$

$m = -1$



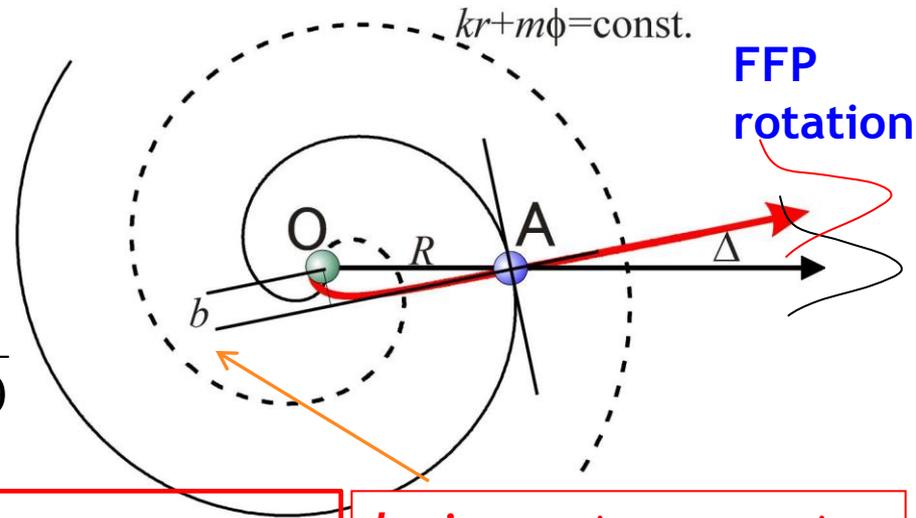
Rotation of the forward direction of the wave by orbital angular momentum

$$\Psi \propto \frac{e^{ikr}}{r} Y_{lm}(\theta, \phi)$$

$$\propto \frac{e^{ikr}}{r} \Theta_{lm}(\theta) e^{im\phi}$$

Phase $\exp[i(kr+m\phi)]$

Rotation $\Delta = \tan^{-1} \frac{m}{kR \sin^2 \theta} \cong \frac{m}{kR \sin^2 \theta}$



Classical Angular momentum

(angular momentum)=(momentum) × (impact parameter)

$$m\hbar = \hbar k \times b$$

$$\Delta_{//} = \sin^{-1} \frac{b}{R_{//}} = \sin^{-1} \frac{m}{kR_{//}}$$

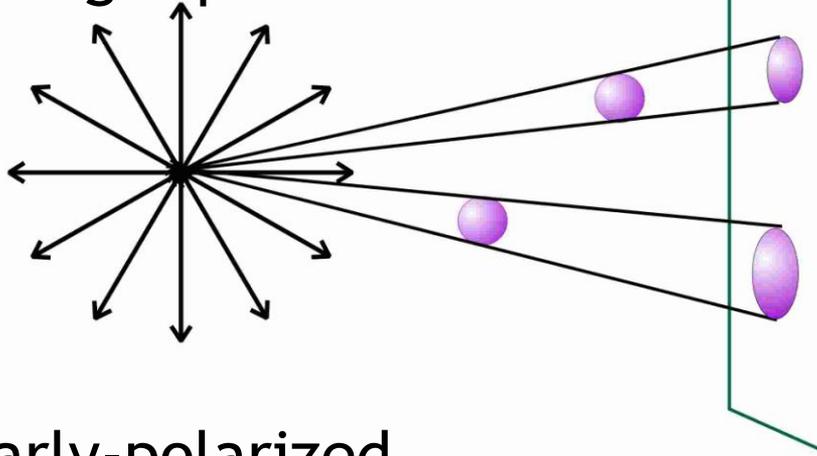
$$\rightarrow \Delta = \sin^{-1} \frac{m}{kR \sin^2 \theta}$$

b : impact parameter is not zero if $m > 0$

H. Daimon, T. Nakatani, S. Imada, S. Suga, Y. Kagoshima, and T. Miyahara, Jpn. J. Appl. Phys. 32 Part 2, (1993) L1480.

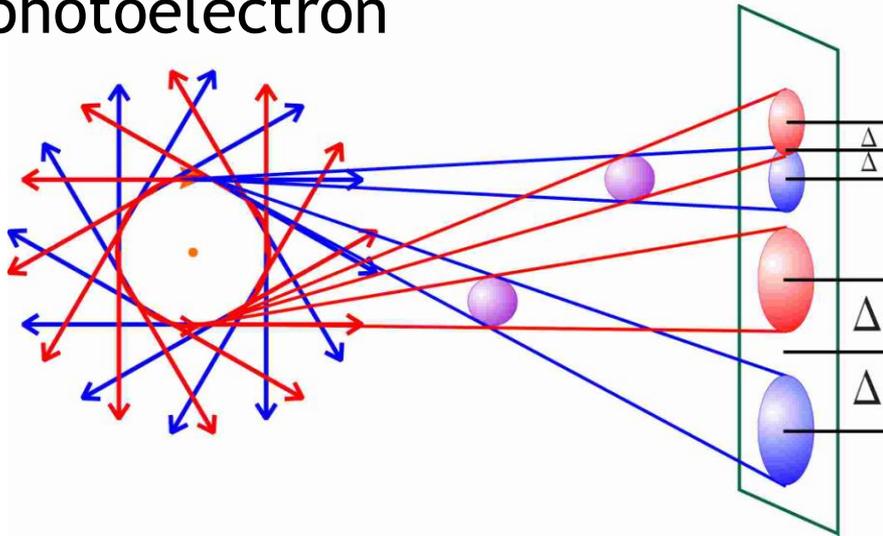
Direction of FFP for normal and circularly-polarized light

Normal light photoelectron



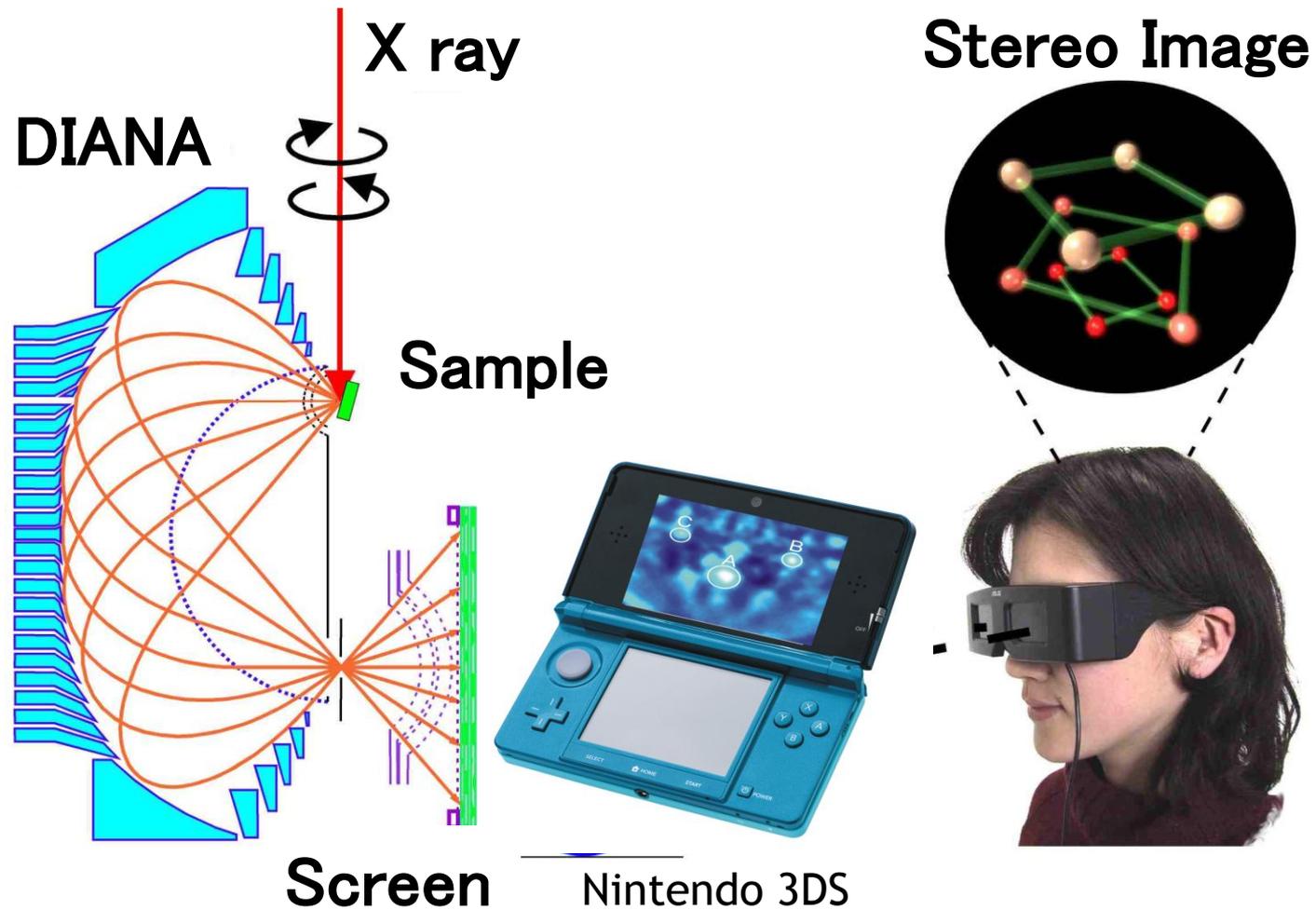
Projected atomic image on the screen

Circularly-polarized light photoelectron



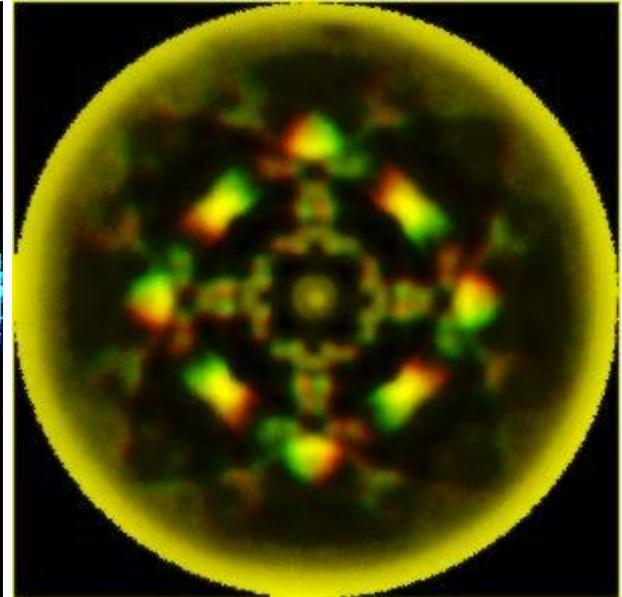
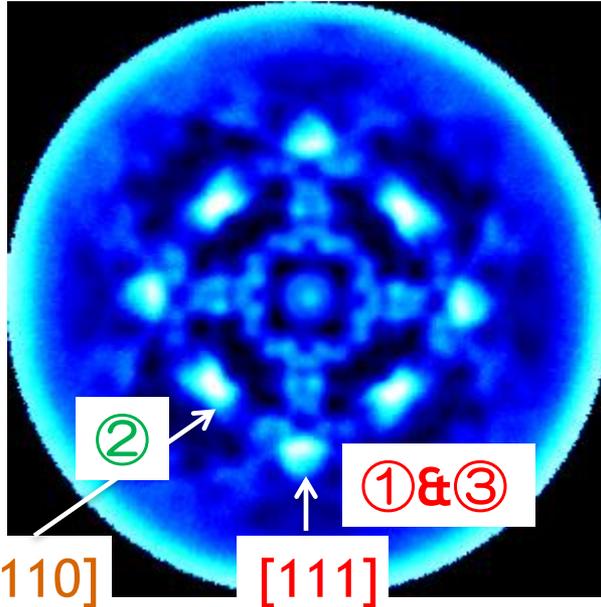
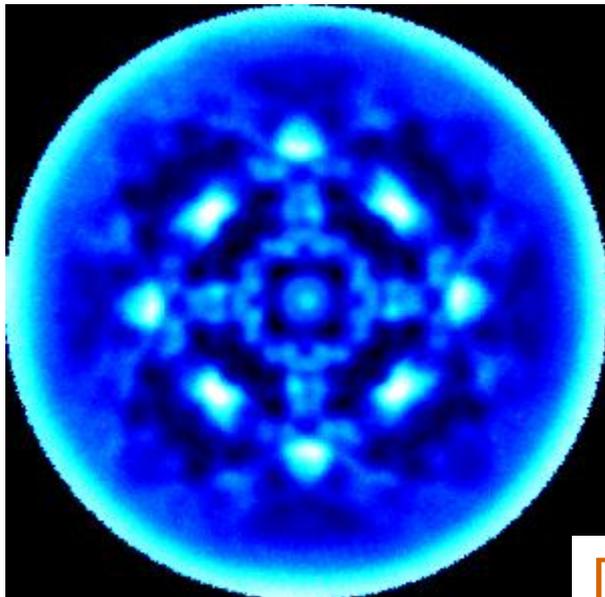
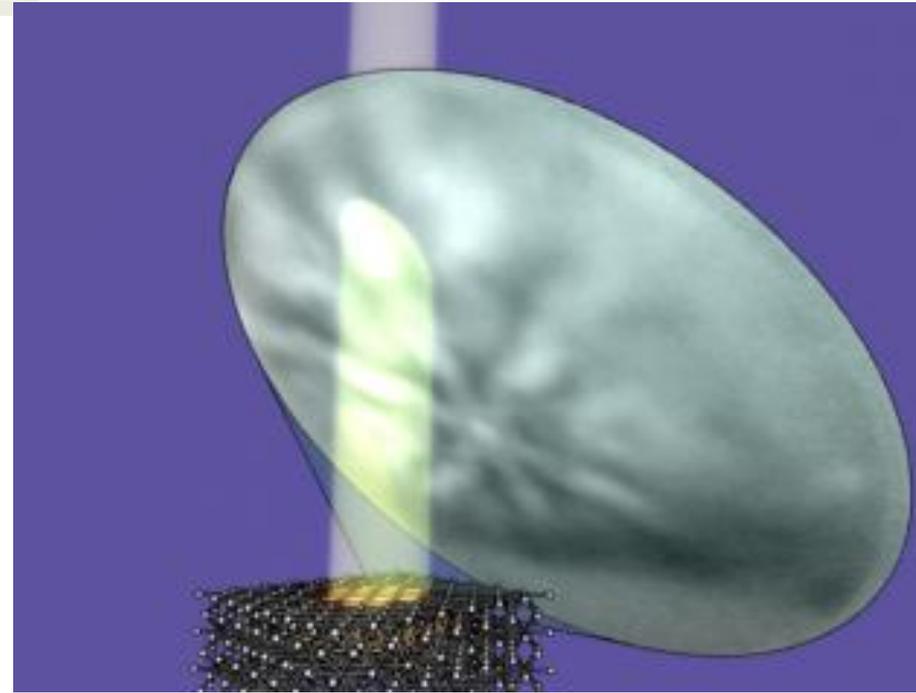
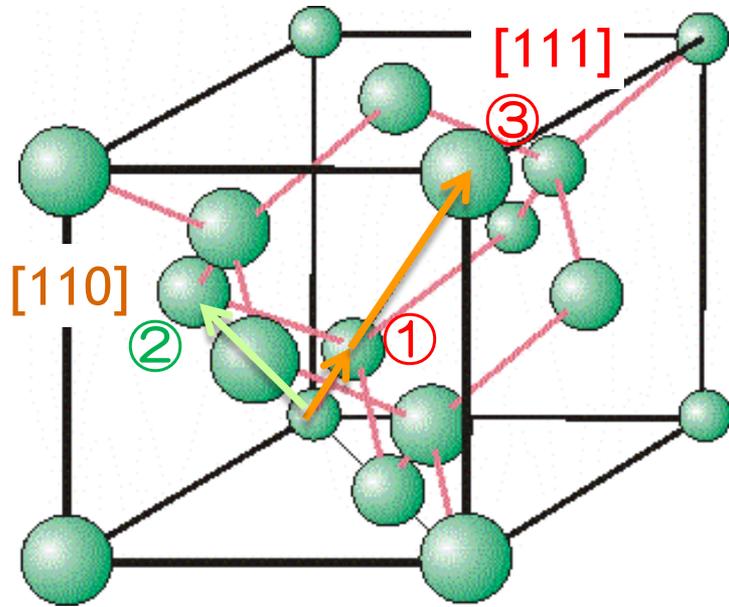
Parallax of Atomic image on the screen

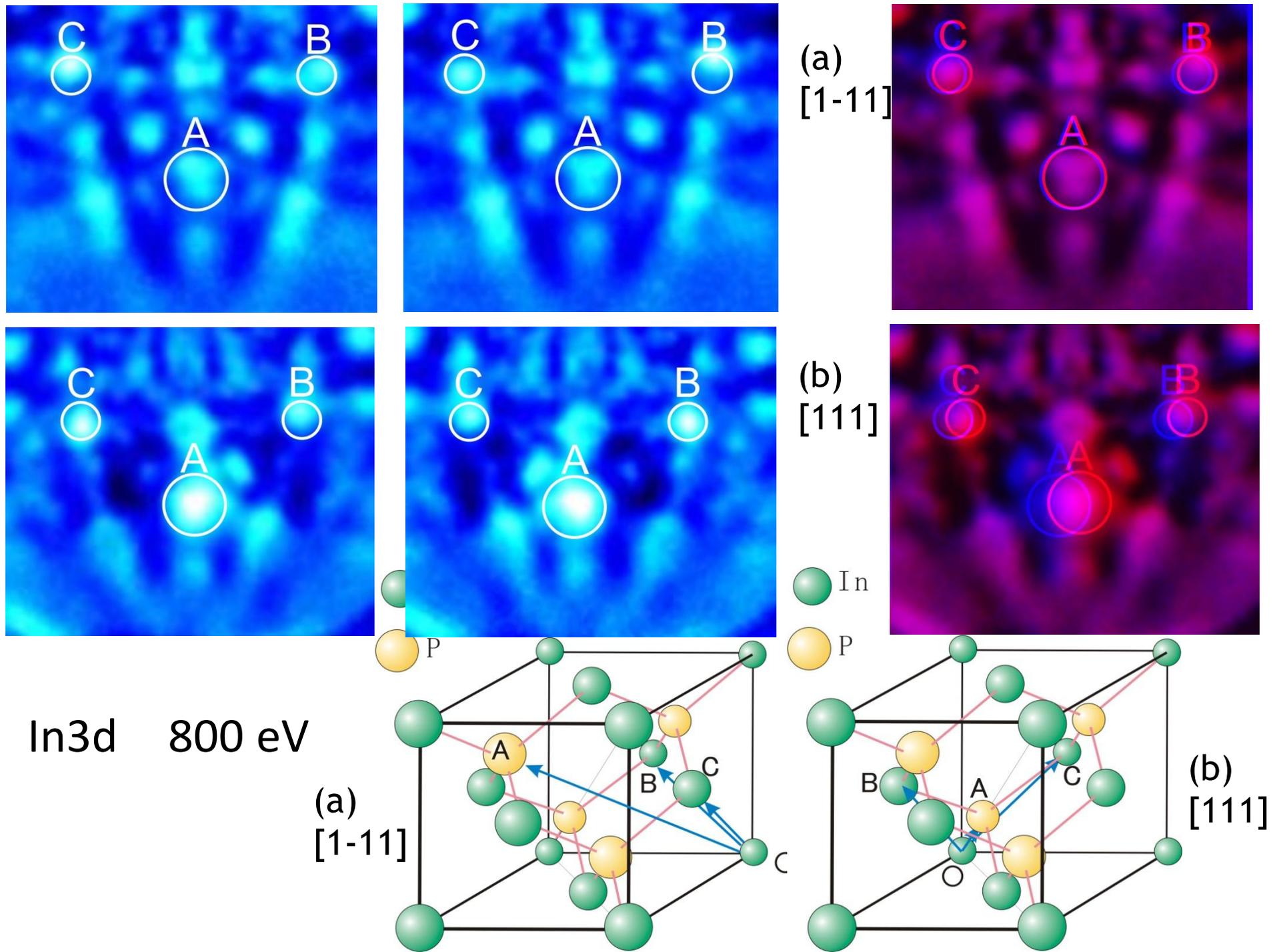
Real-time direct observation of non-periodic 3D atomic arrangement

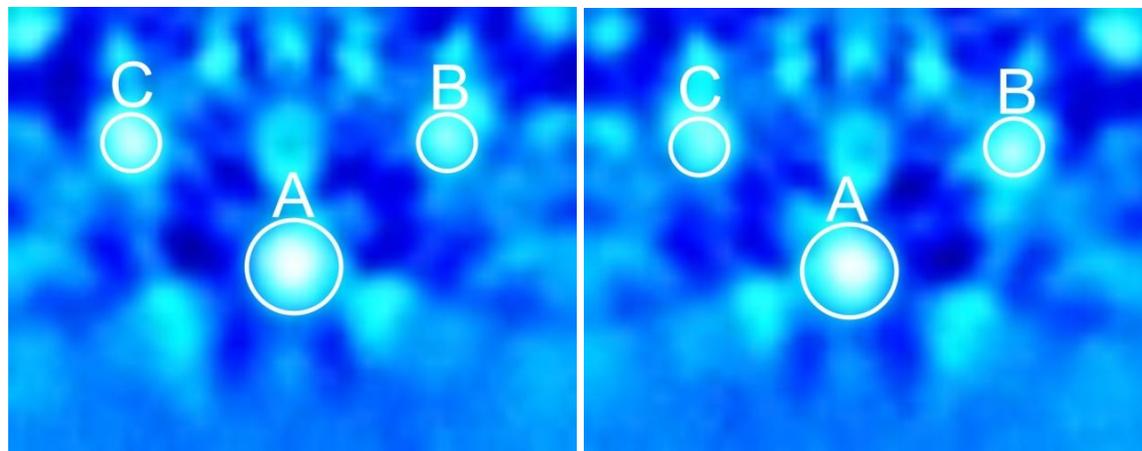


2π -steradian stereo photograph

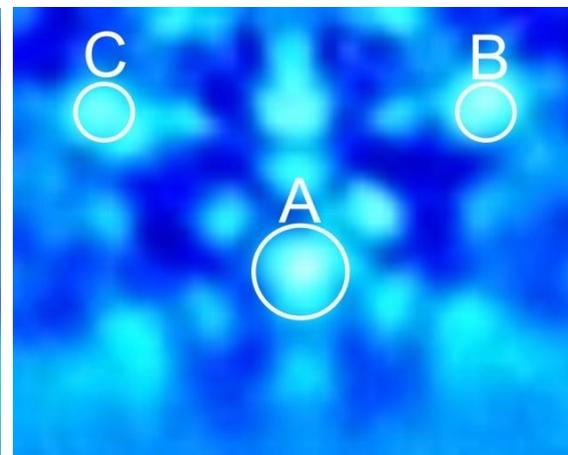
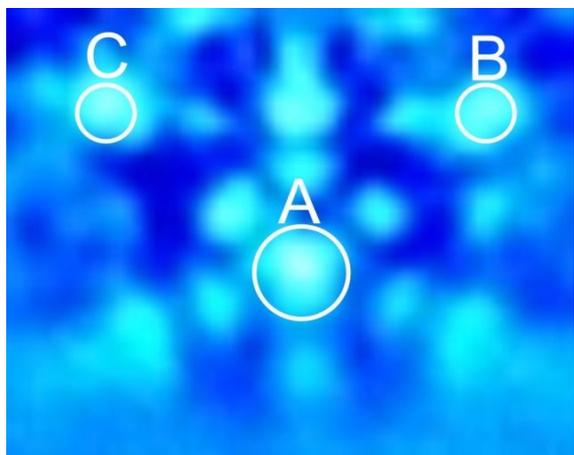
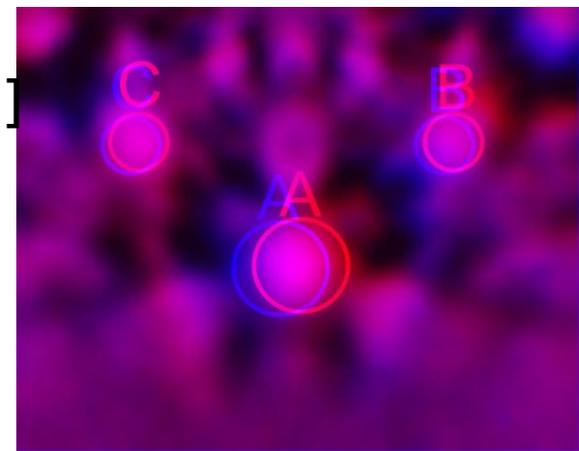
Si(001)



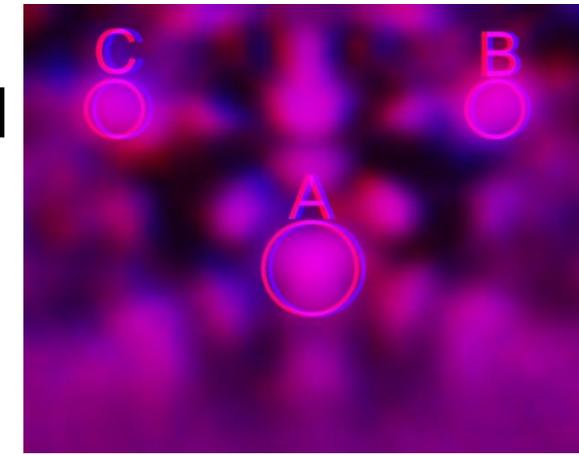




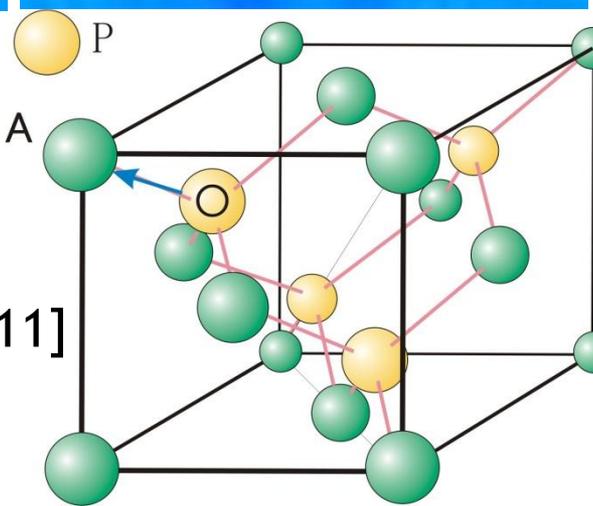
(a)
[1-11]



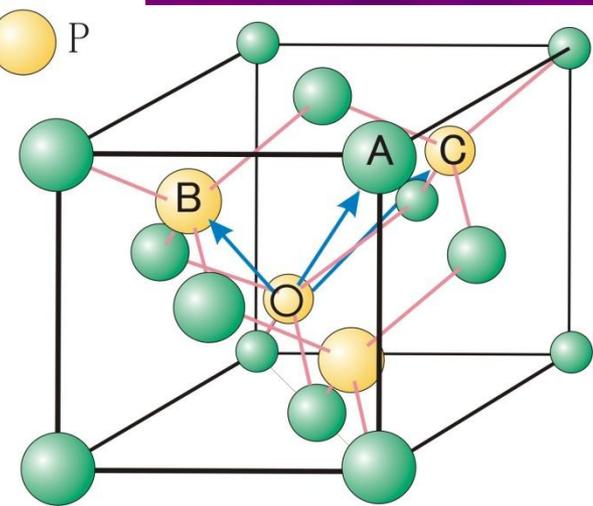
(b)
[111]



● In



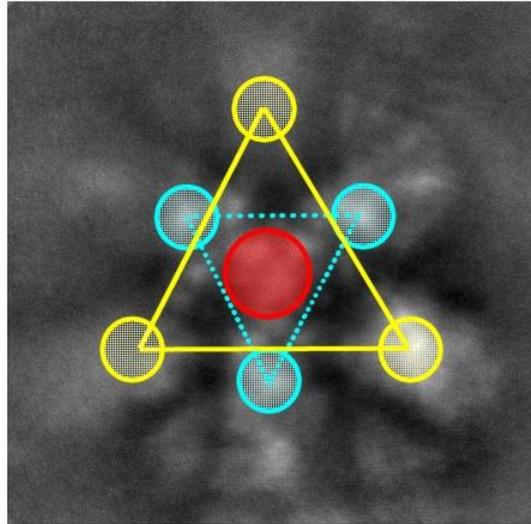
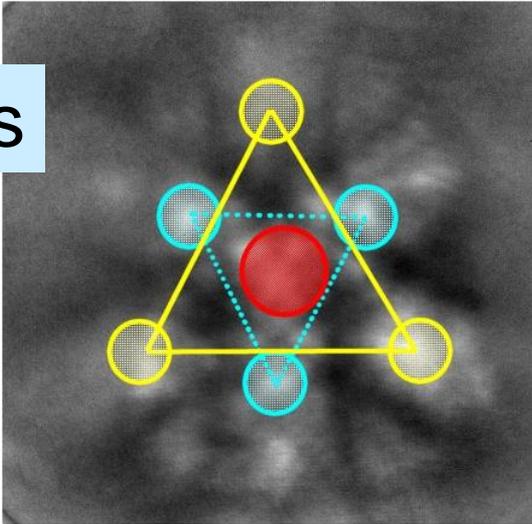
(a)
[1-11]



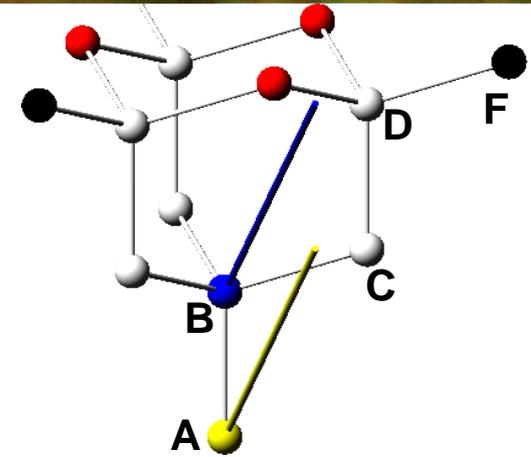
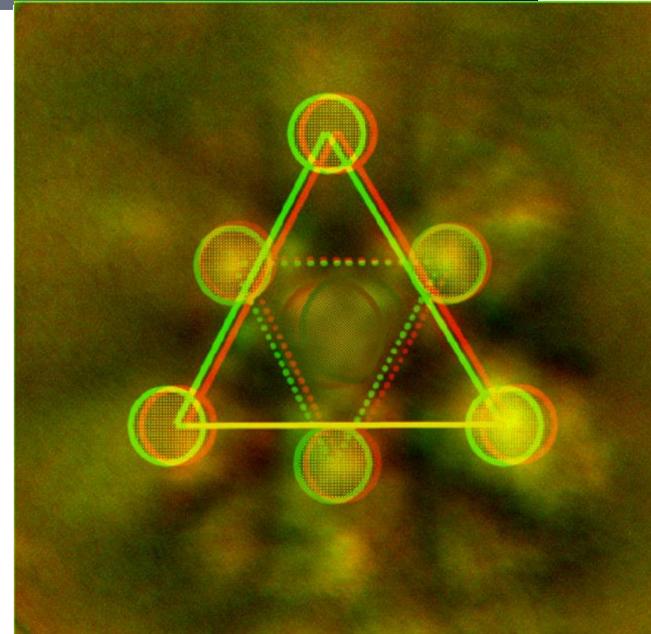
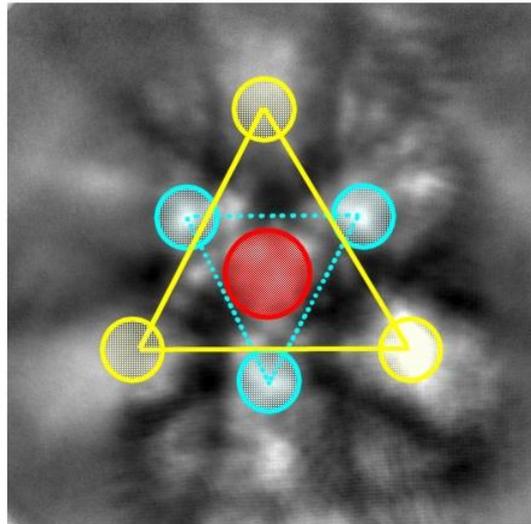
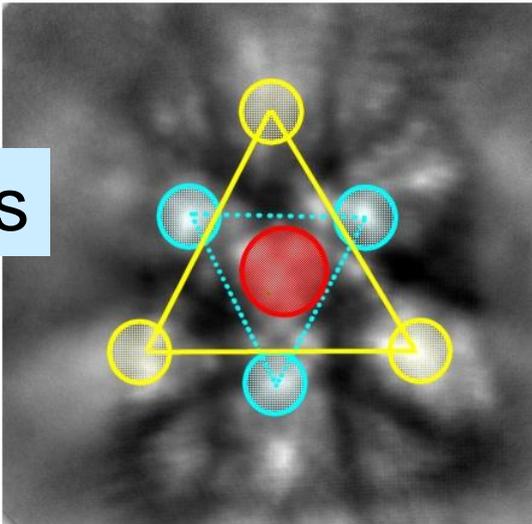
(b)
[111]

P2p 800 eV

B 1s



C 1s



One substitutional site

C1s & B1s patterns are *similar*

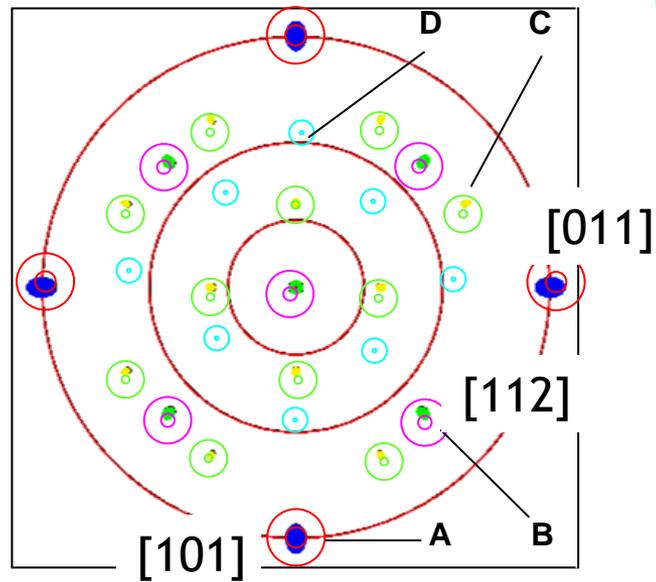
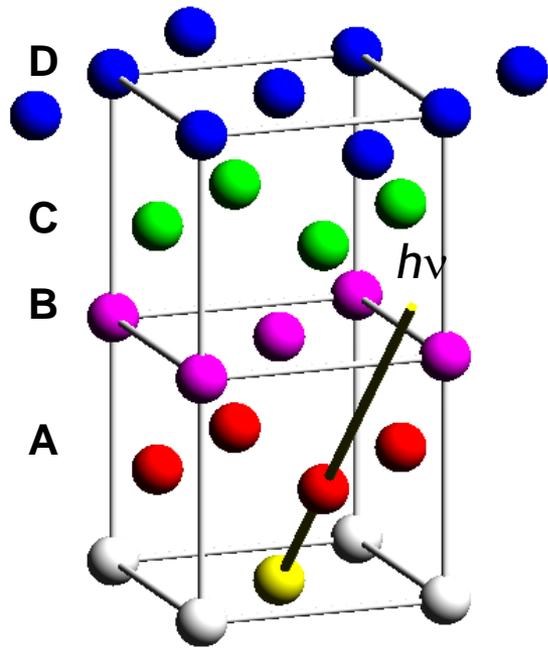
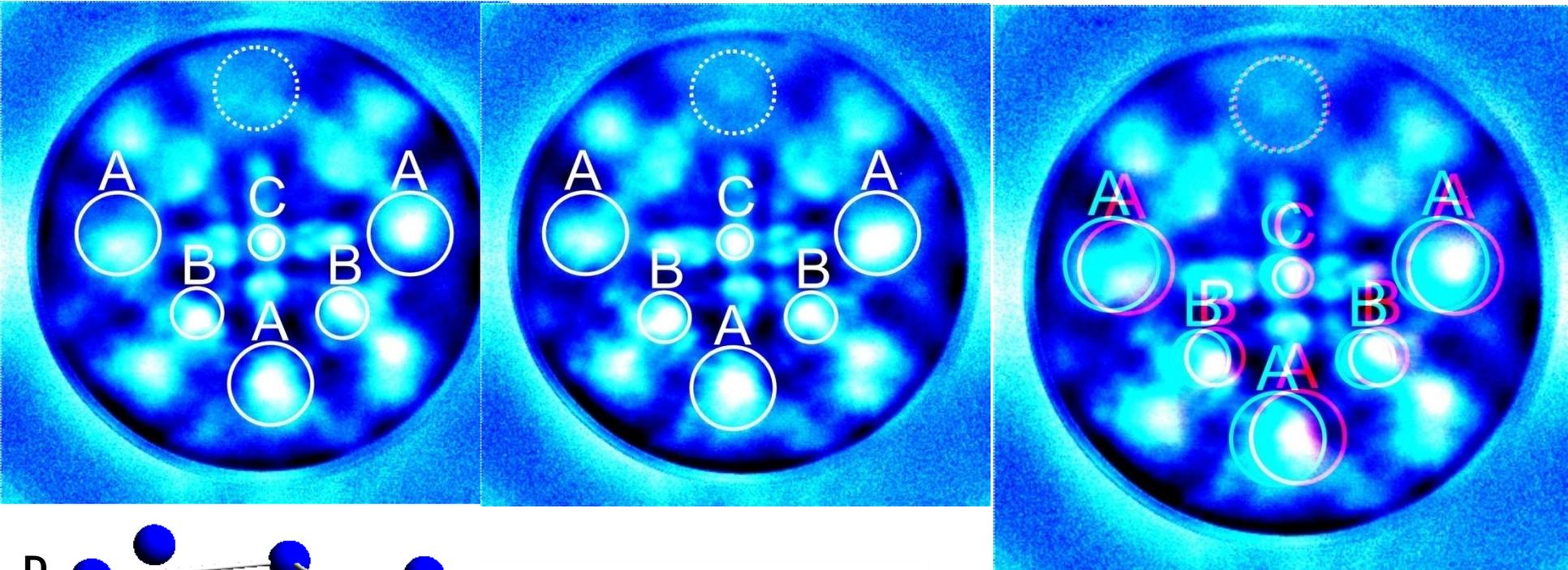
Atomic arrangement around 2% impurity could be clarified

Cu(001)

E_k 600 eV

$h\nu$ 680.6 eV

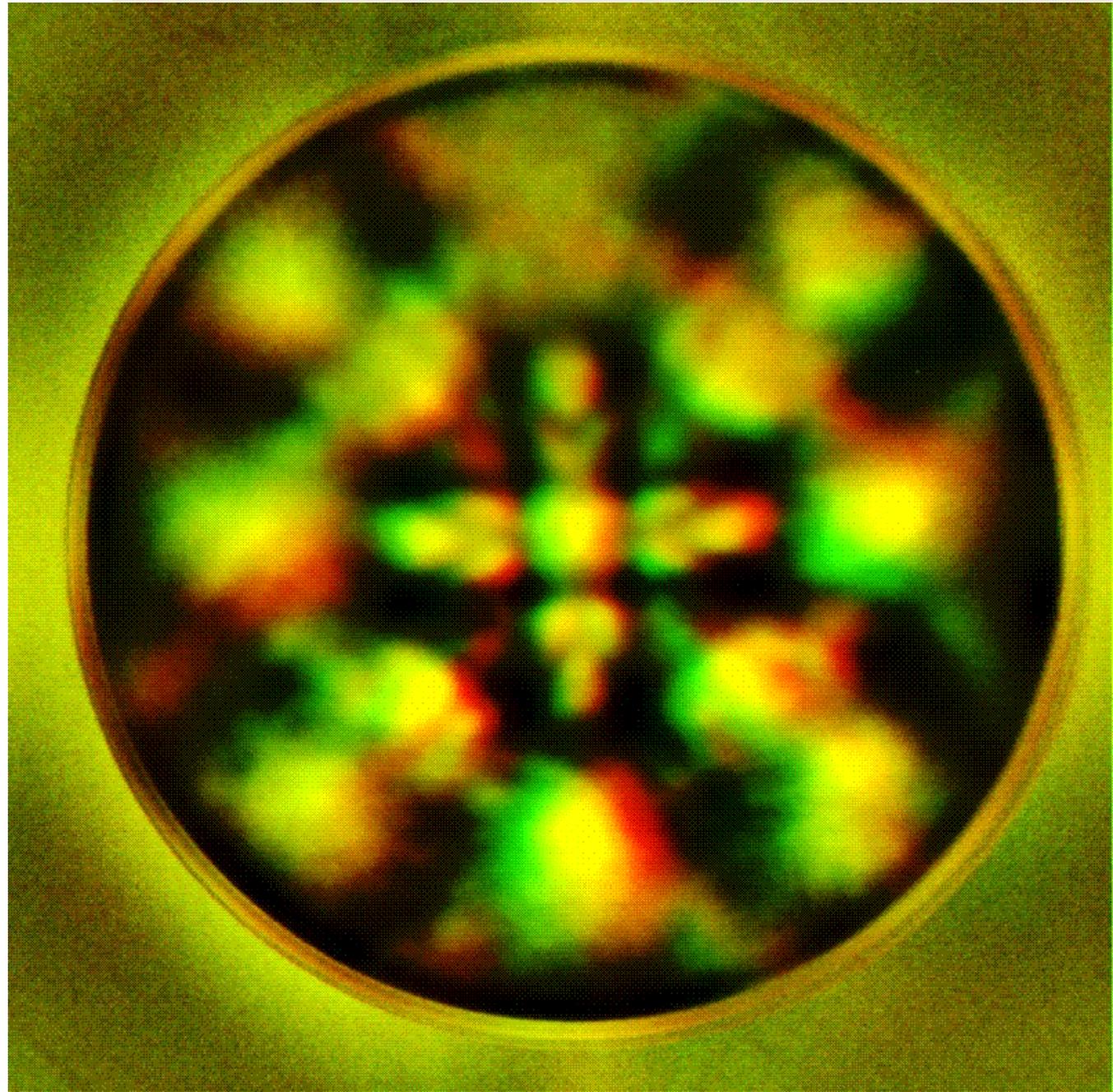
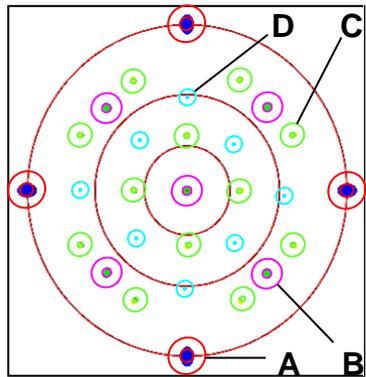
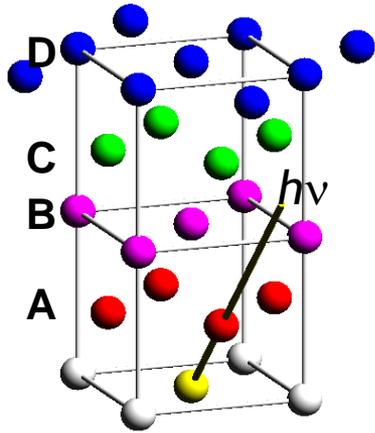
Cu $3p_{3/2}$



Stereo movie of Cu



fcc structure



Stereo-PEEM

- PEEM : $\Delta x = \mu\text{m}$, $\Delta E = 0.1\%$
- Stereo Atomic Image (Circularly polarized-light PEAD)
 $\Delta x = 0.2 \text{ \AA}$, $\Theta = \pm 60^\circ$

Wide Acceptance Angle (about 1 sr)
Electrostatic Lens (WAAEL)

Lens System

DIANA

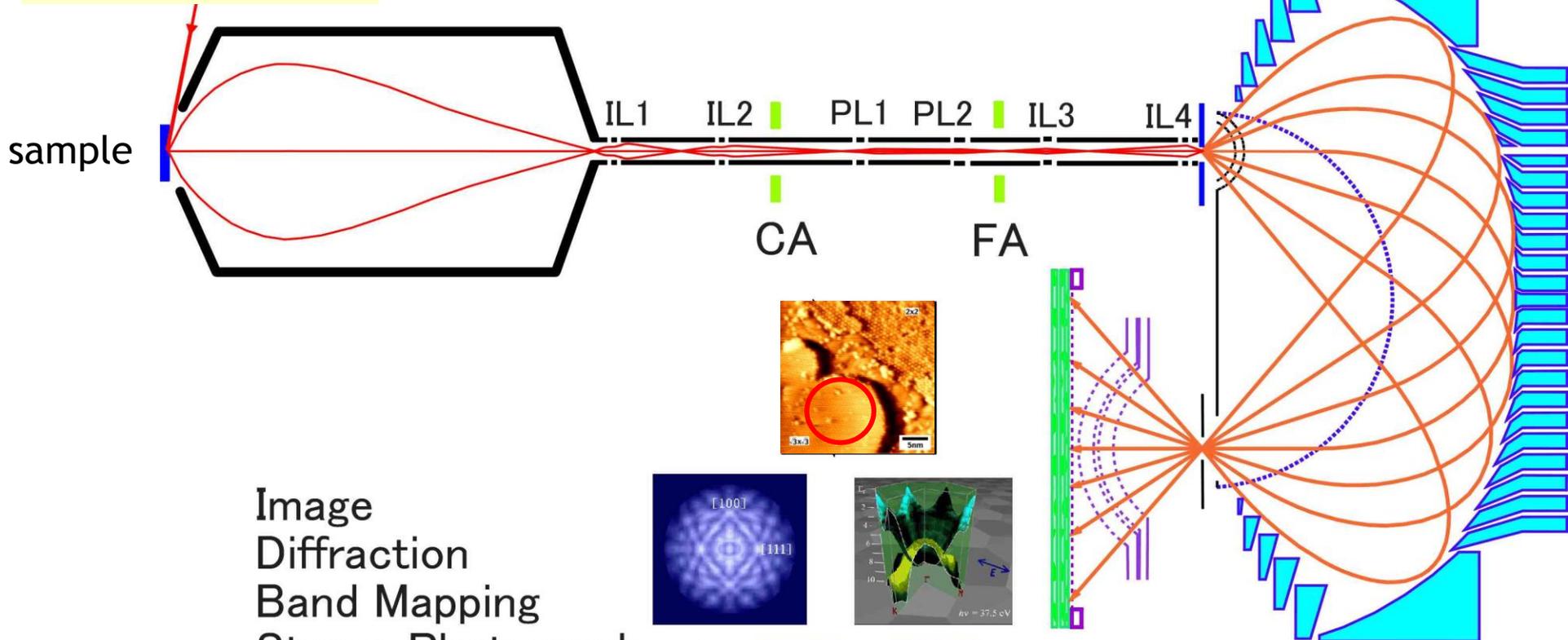
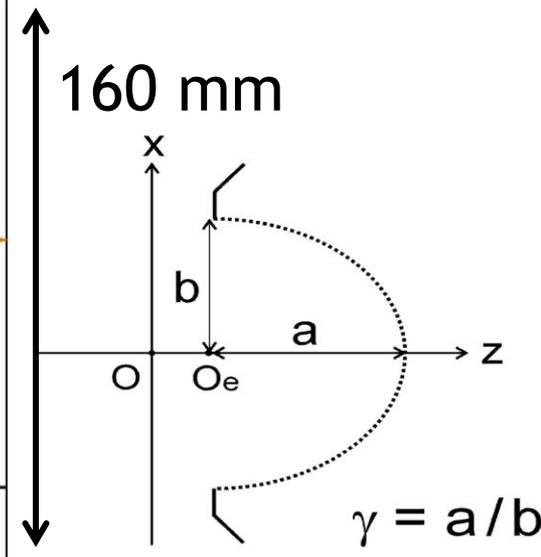
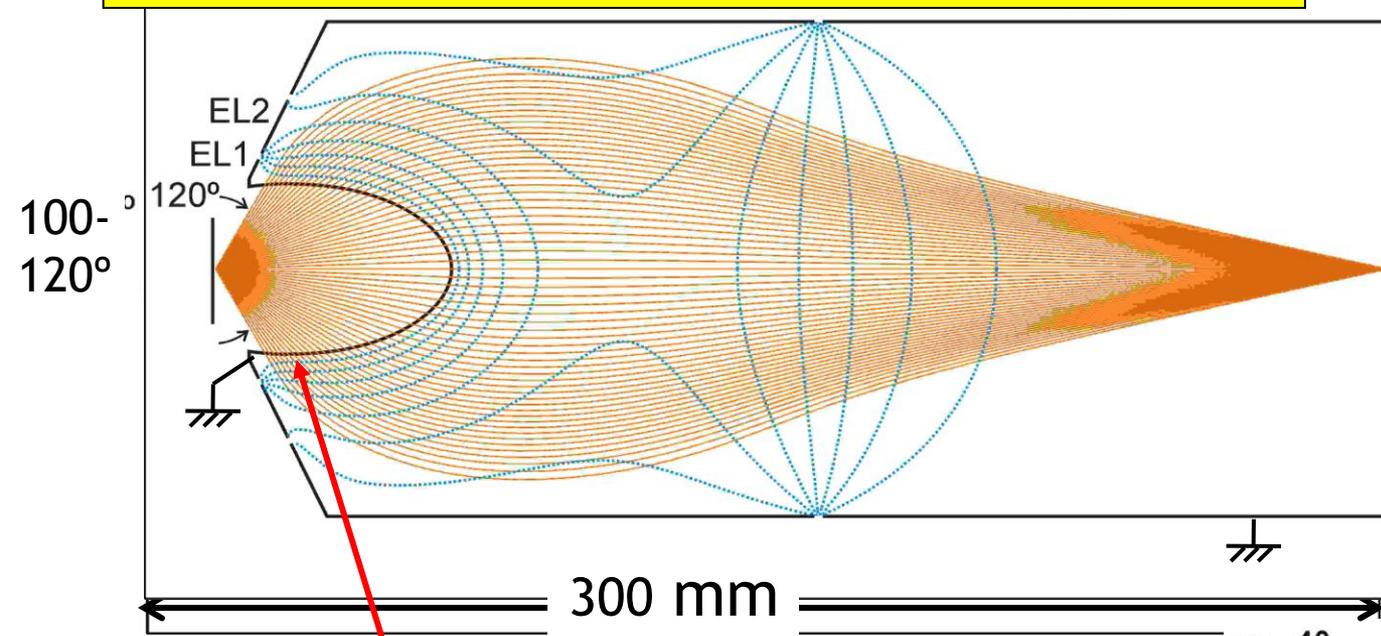


Image
Diffraction
Band Mapping
Stereo Photograph

For selected micro-area!

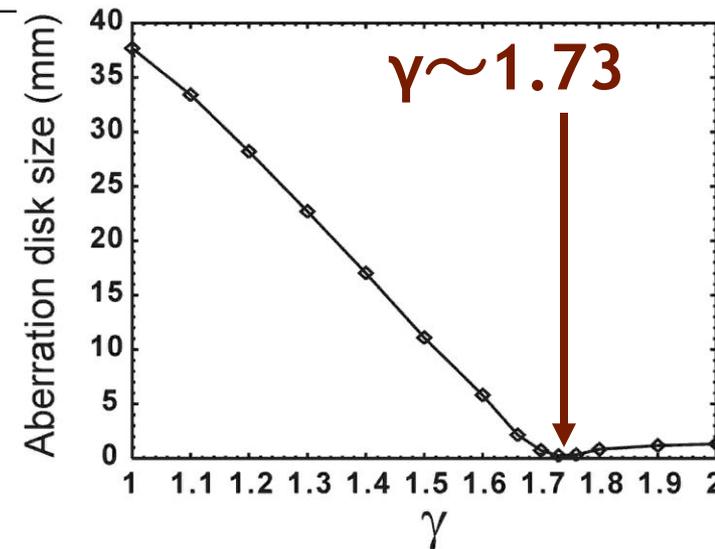
Wide Acceptance Angle Electrostatic Lens (WAAEL)

Acceptance angle $\pm 50^\circ \sim \pm 60^\circ$

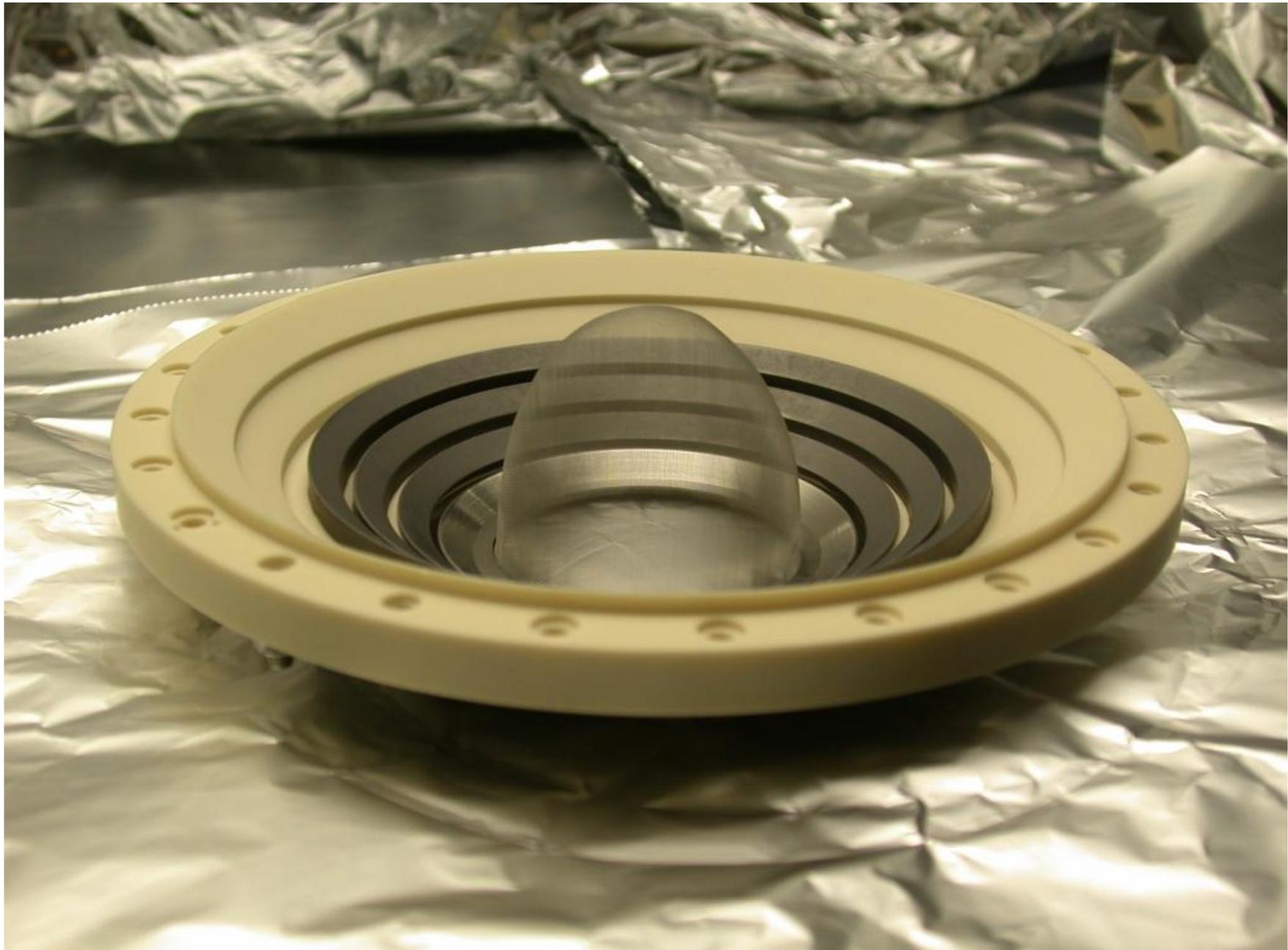


Nearly ellipsoidal shape mesh

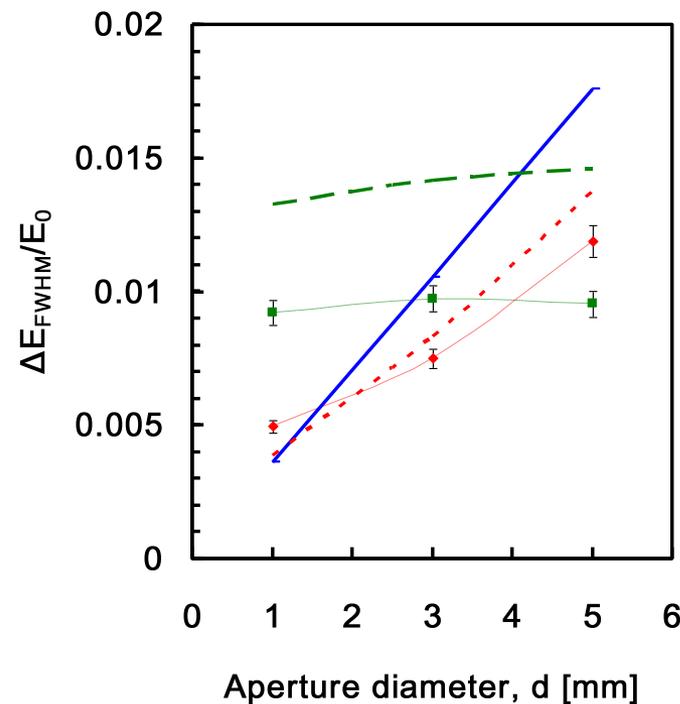
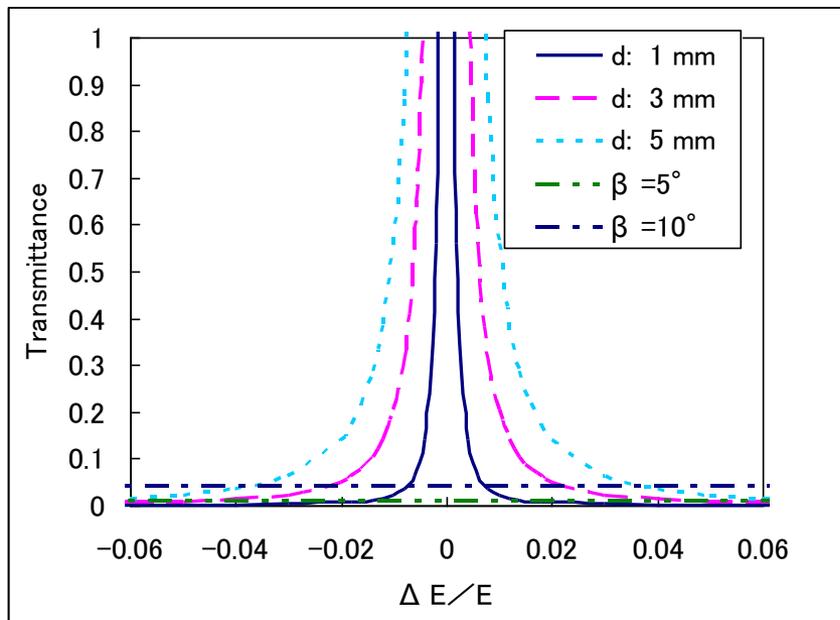
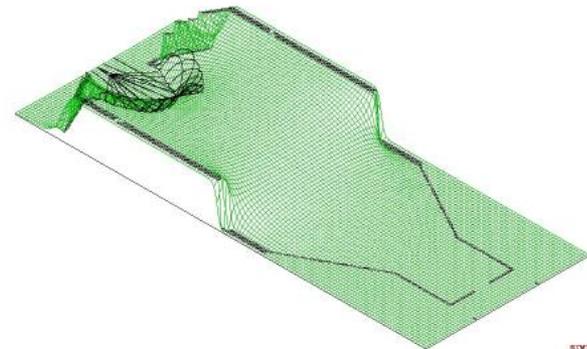
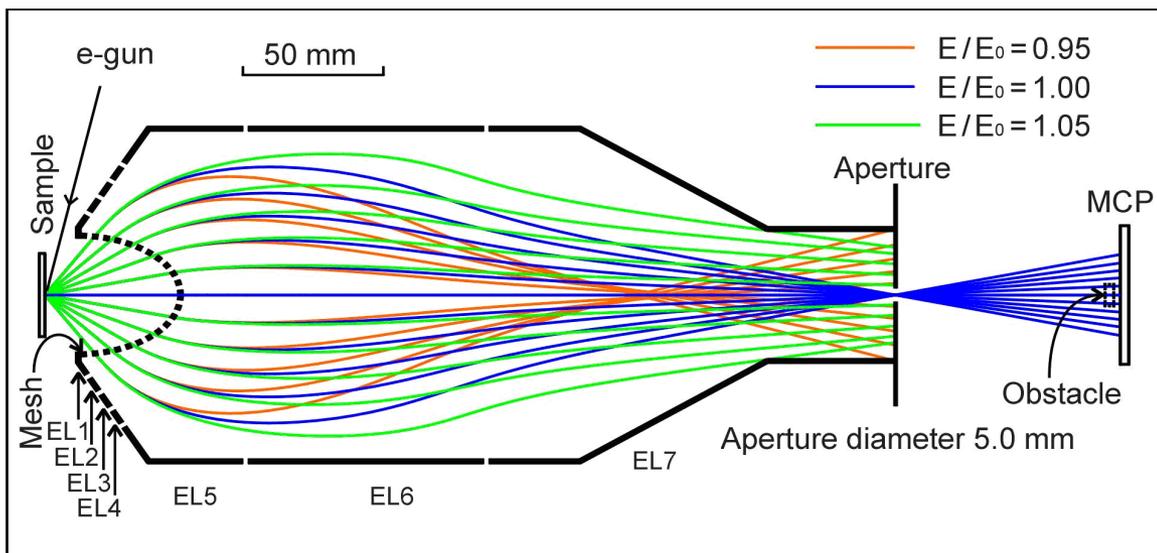
Sample region : field free
Acceptance angle reduces to 1/5



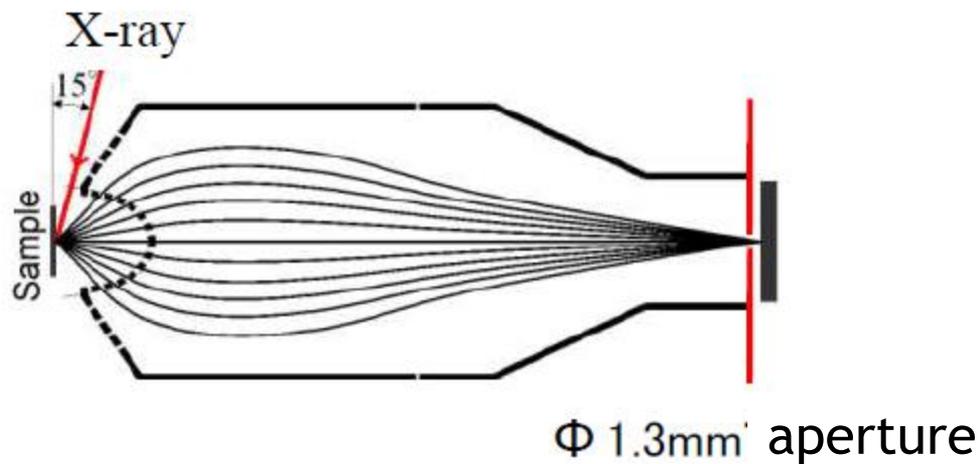
[1] H. Matsuda, H. Daimon, M. Kato and M. Kudo, Phys. Rev. E 71, 066503 (2005)
[2] patent: PCT/jp2004/016602, Japan 2004-208926
[3] L. Tóth, H. Matsuda, T. Shimizu, F. Matsui and H. Daimon, J. Vac. Soc. Jpn. 51, 135 (2008)



Energy analysis of DELMA by energy aperture

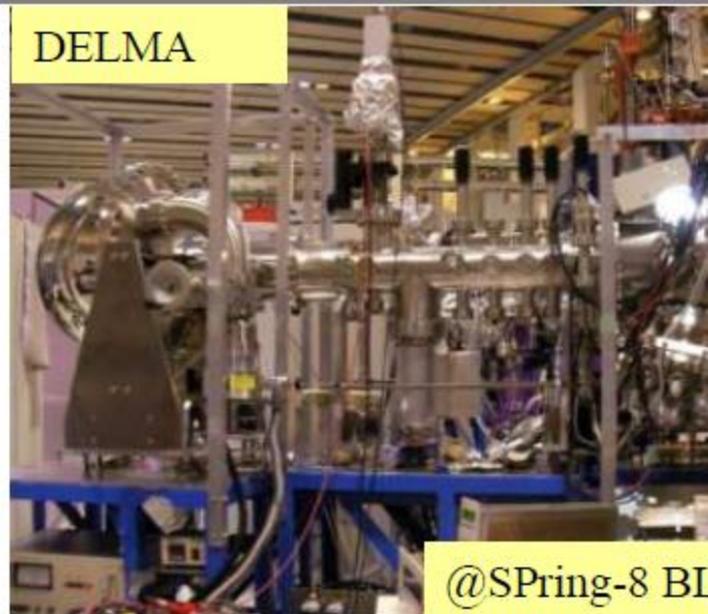
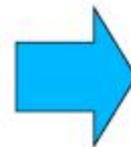
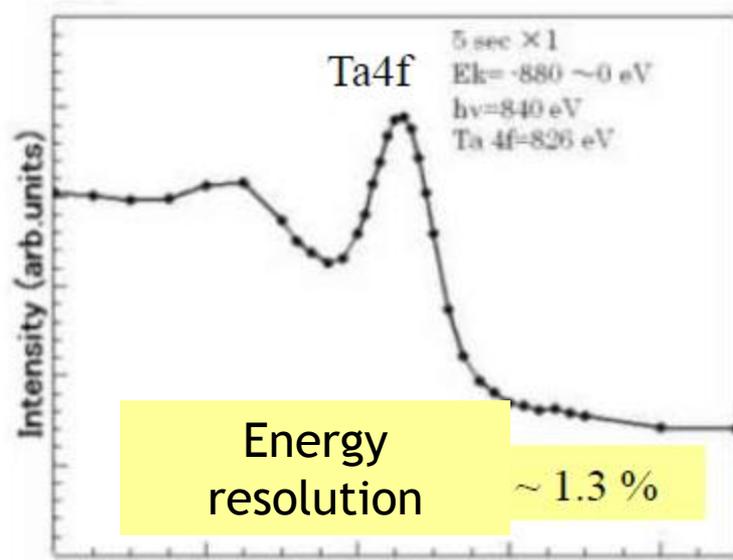


Photoelectron Spectrum



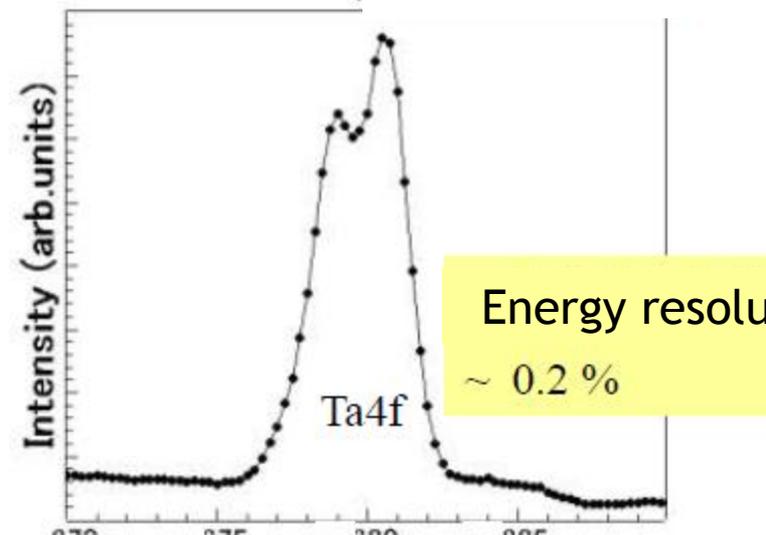
Sample: TaS₂

Spectrum obtained by energy aperture



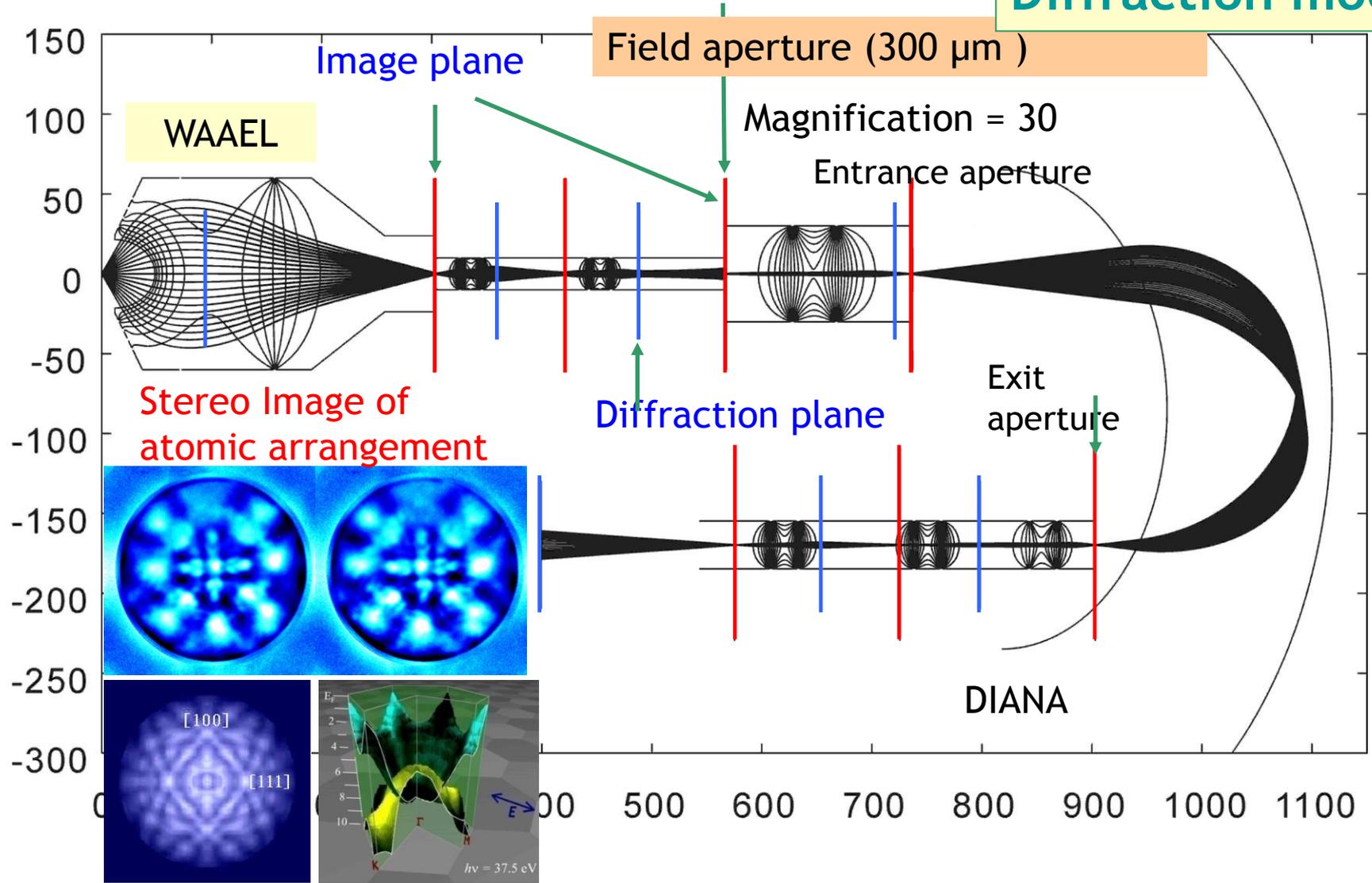
DELMA+HSA

(Slit width is 3 mm)



DELMA: Display-type Ellipsoidal Mesh Analyser

Diffraction mode

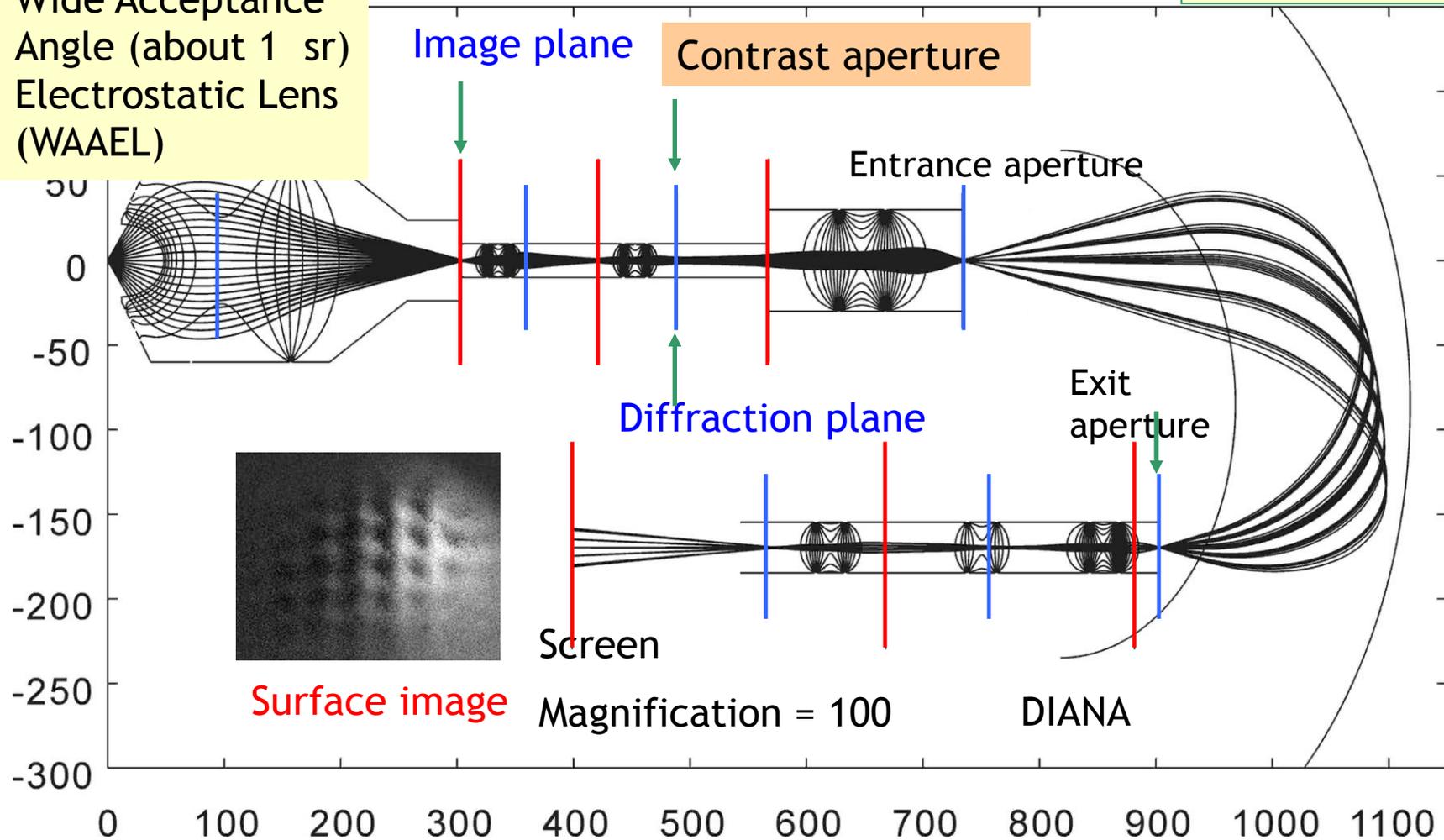


Diffraction Band structure

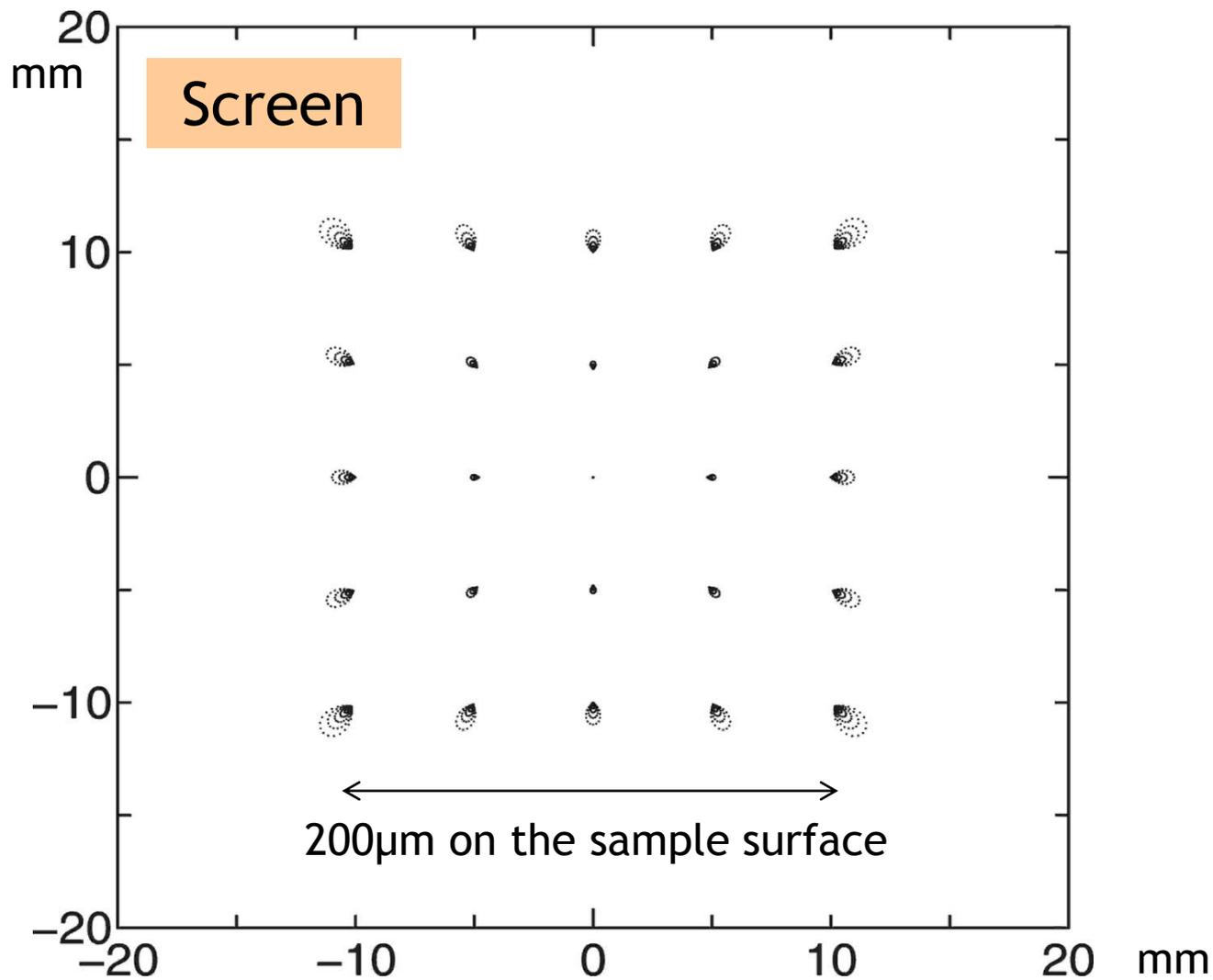
DELMA: Display-type Ellipsoidal Mesh Analyser

Imaging mode

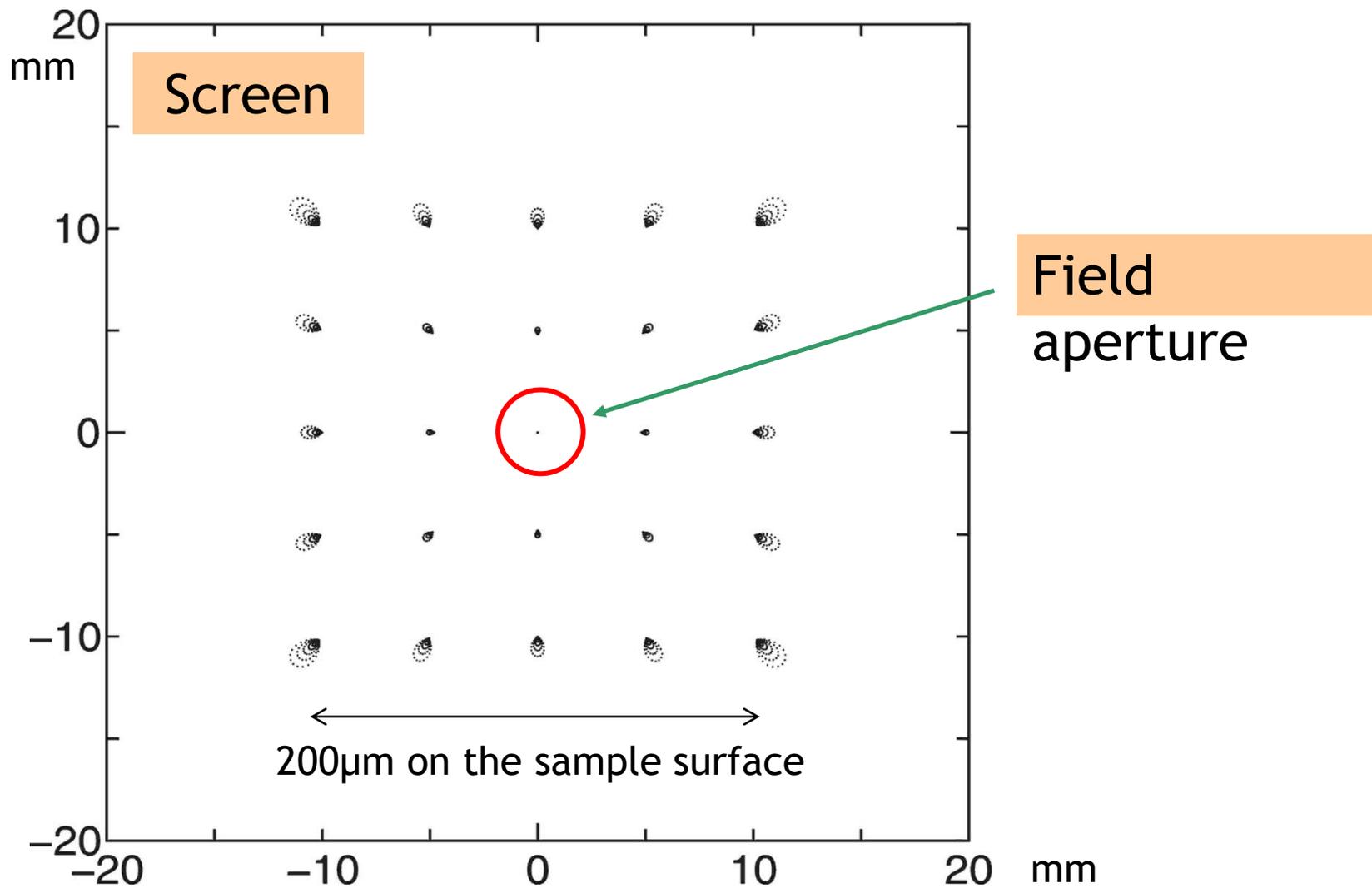
Wide Acceptance
Angle (about 1 sr)
Electrostatic Lens
(WAAEL)



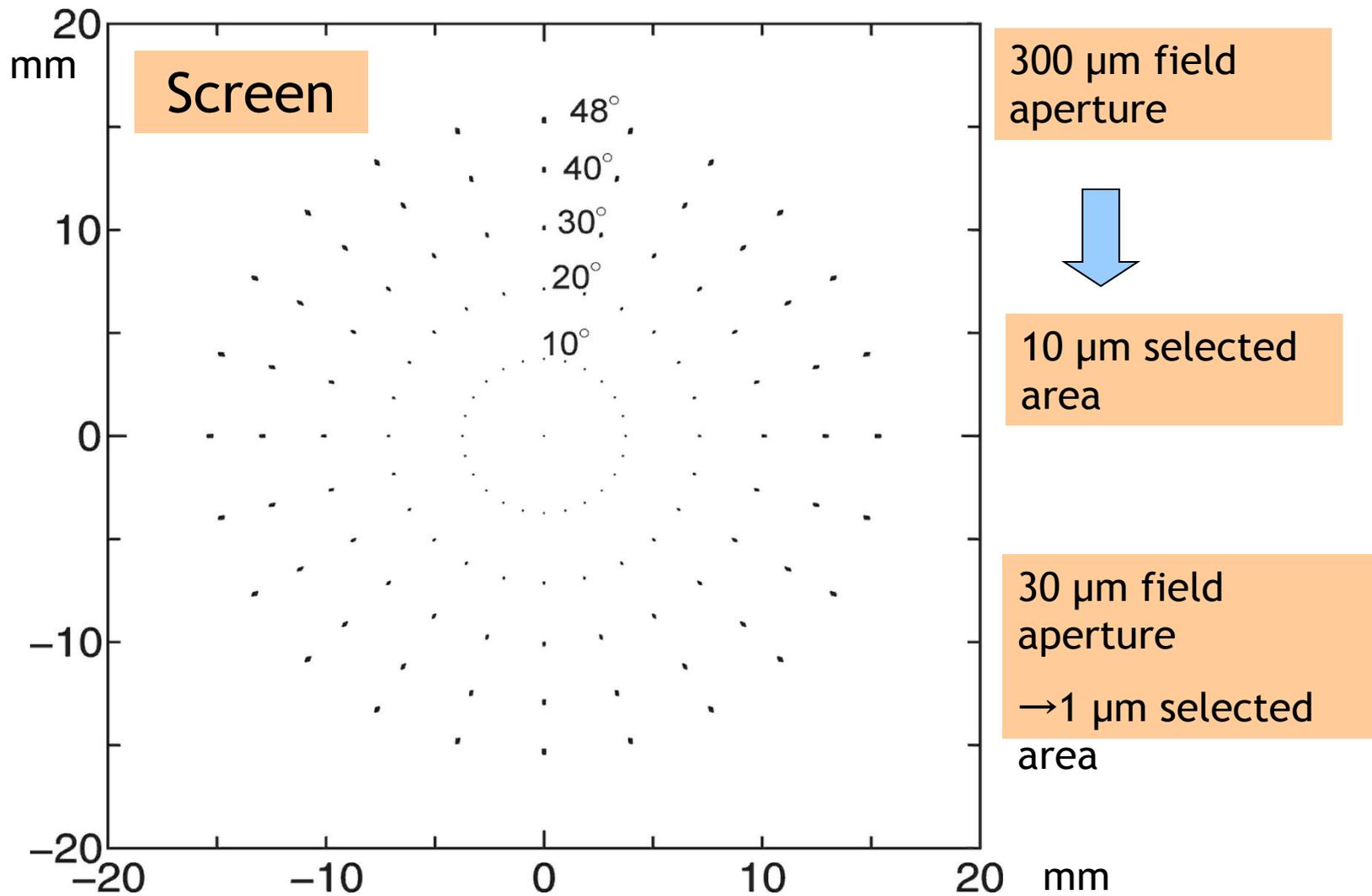
Off-Axes Point-source image



Point-source image



Point-source image



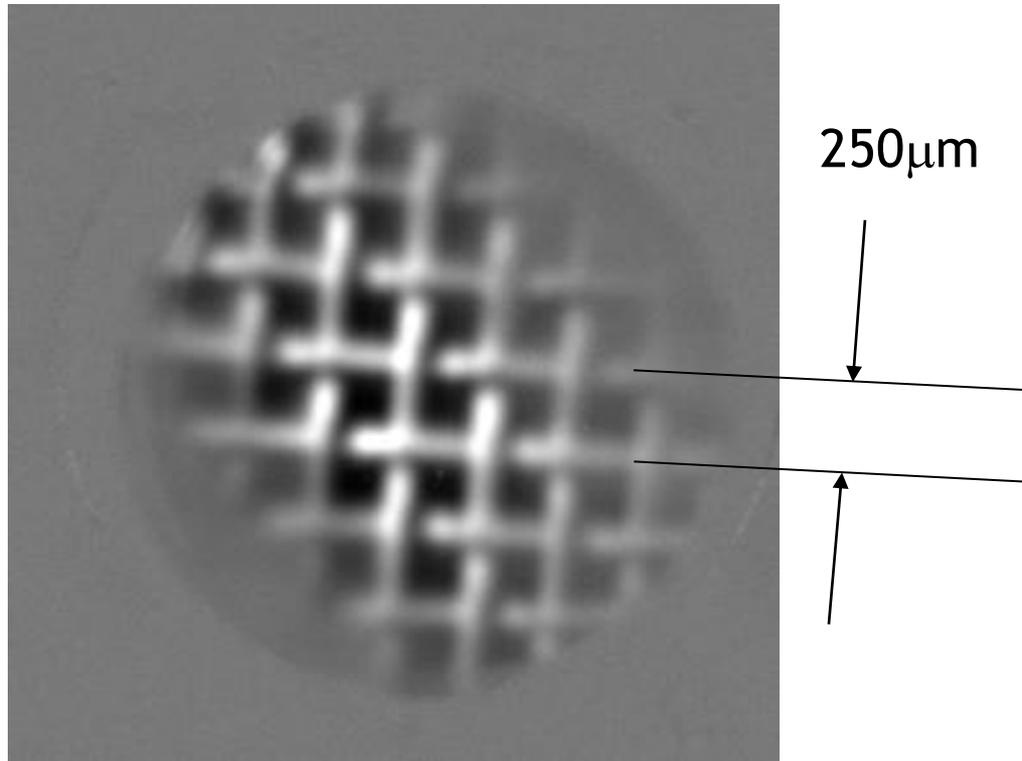
Test experiments using an electron gun

Imaging mode

Sample: SUS316 woven mesh (#100, $\phi_{\text{wire}}=50 \mu\text{m}$)

$E_k=1000\text{eV}$

Magnification ~ 10



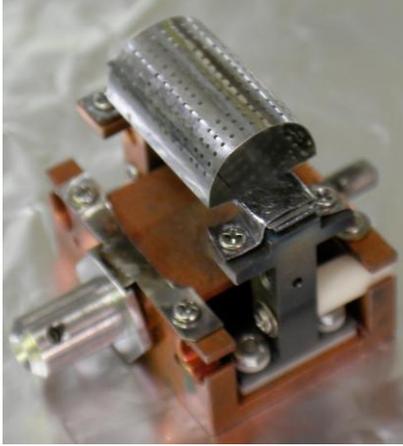
Contrast aperture : the largest one (6mm)

Spatial resolution $\sim 20 \mu\text{m}$

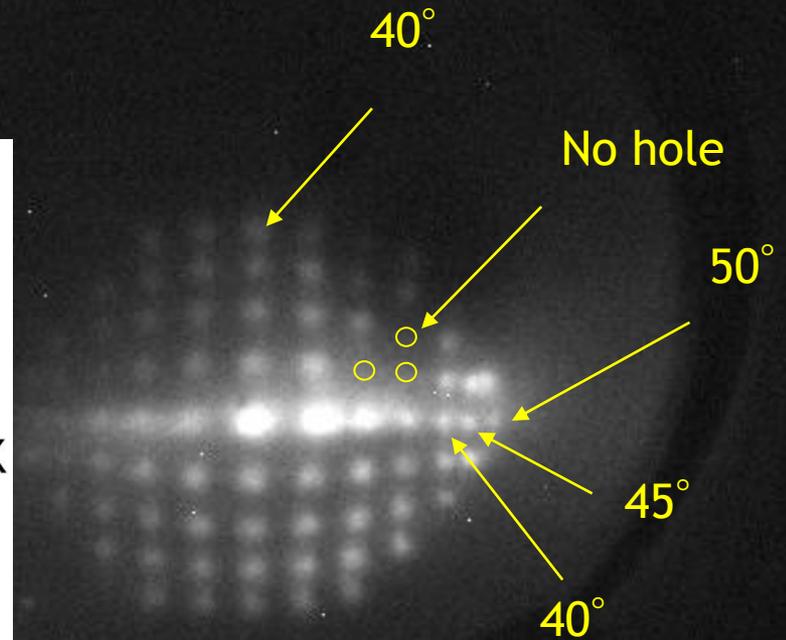
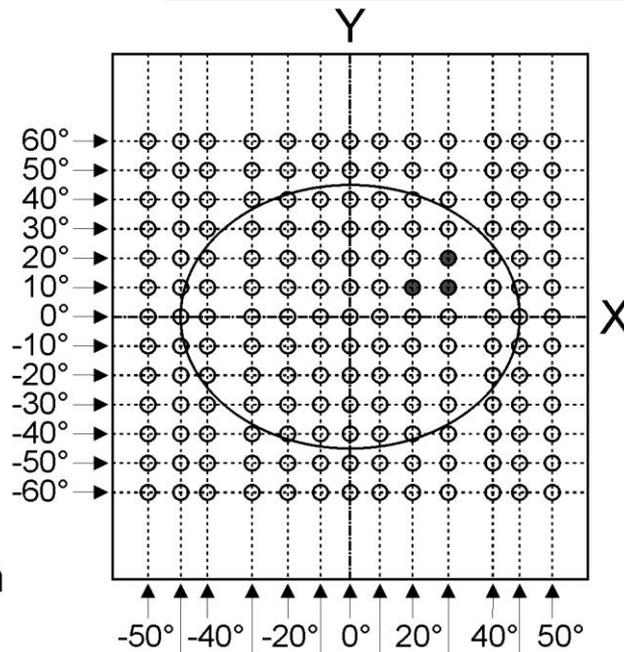
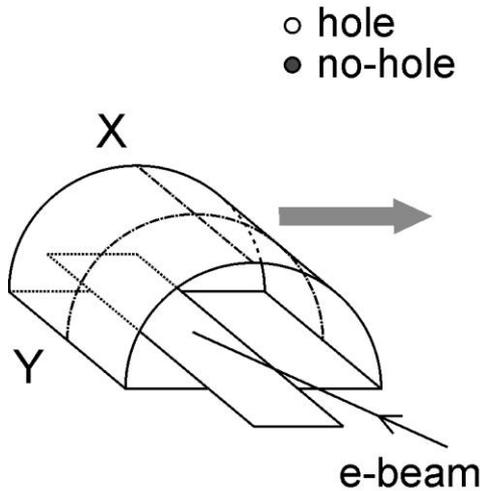
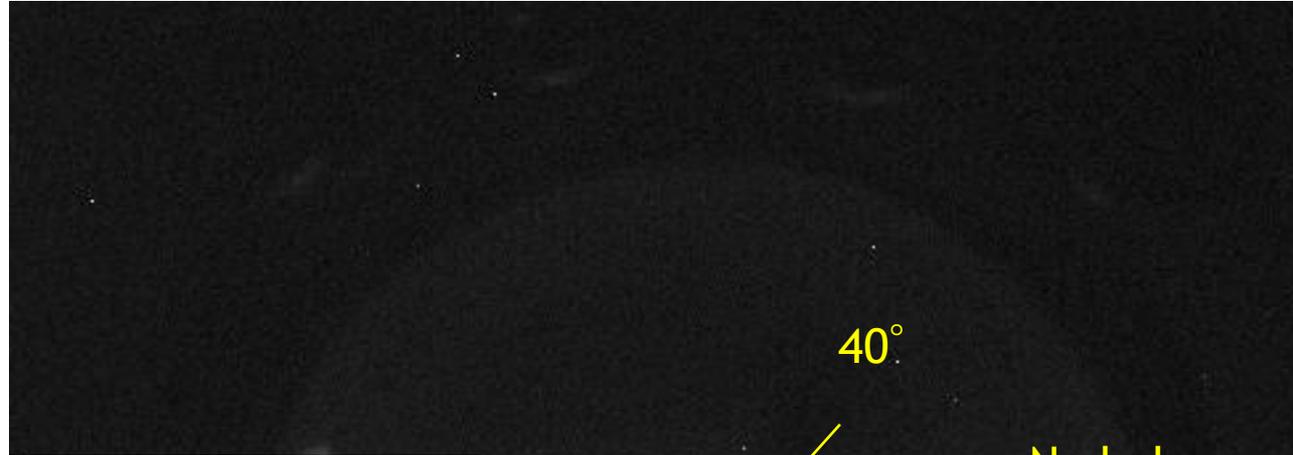
Test experiments using an electron gun

Angular mode

Angle test device

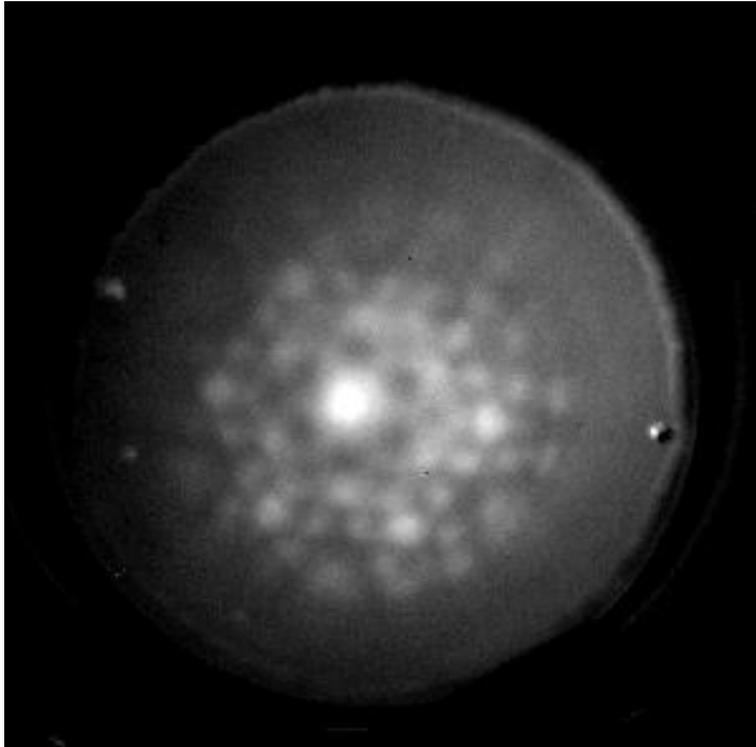


$E_k=1000\text{eV}$



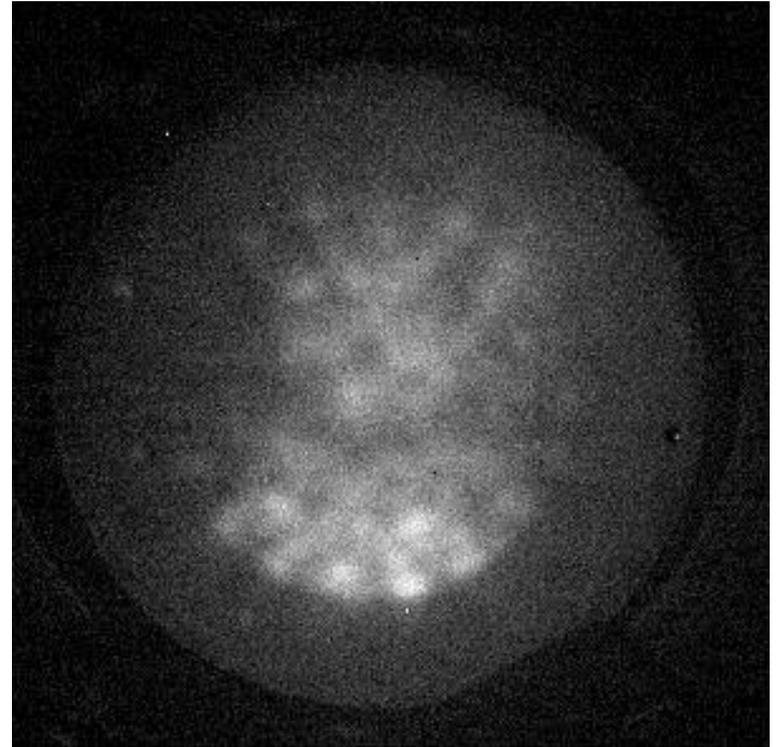
Sample: single crystalline graphite
 $h\nu=990$ eV $E_k=700$ eV (BL07LSU)

Horizontal



vs.

Vertical linear polarization



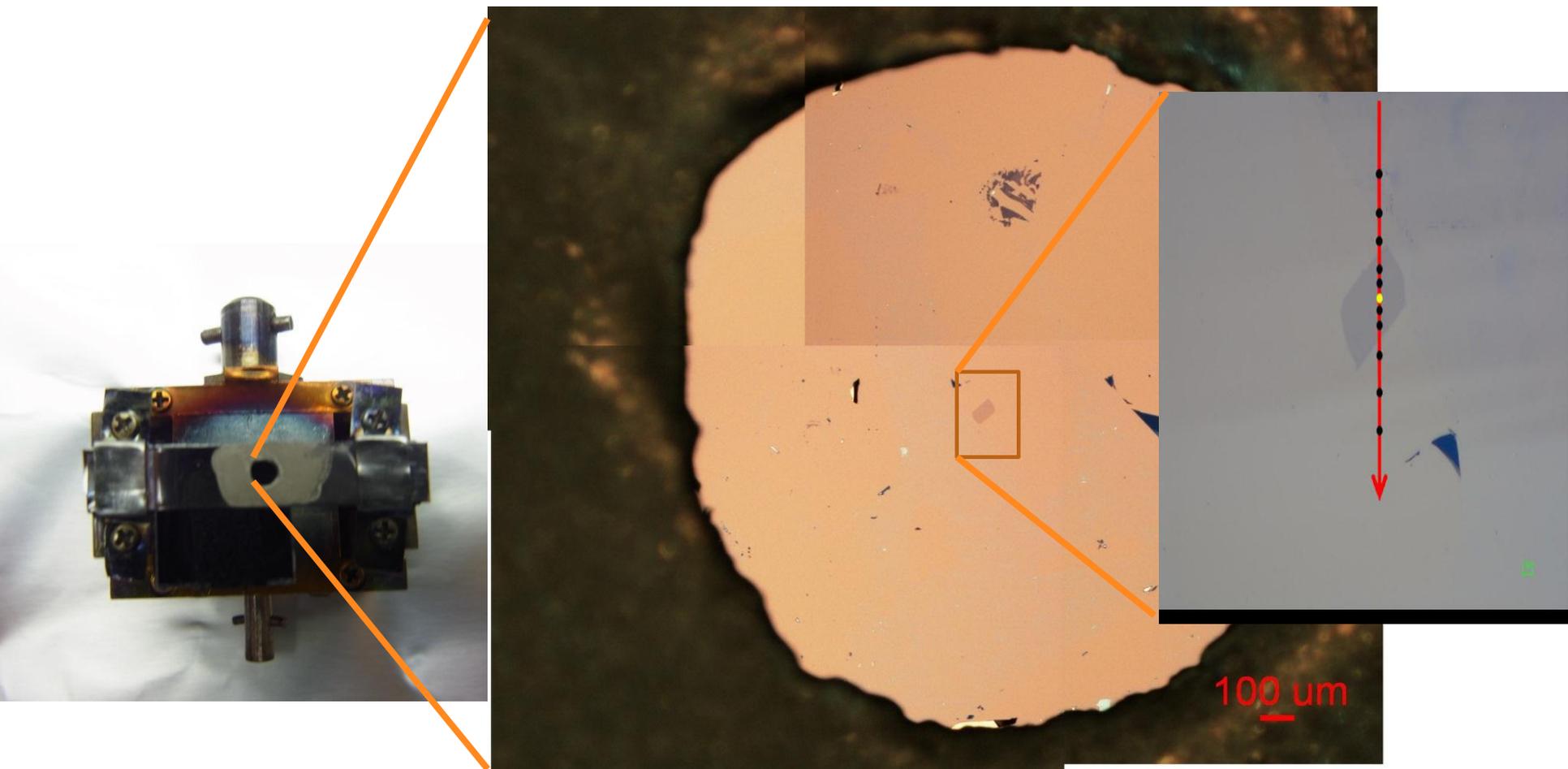
Photoelectron diffraction pattern

NAIST Daimon Group

グラフェンの光電子回折像の測定

奈良先端大・物質創成、JASRI/SPring-8^A

石井良、松井文彦、黄晋二、細川陽一郎、松下智裕^A、森田誠、
北川哲、橋村詩織、藤田将喜、安田馨、大門寛



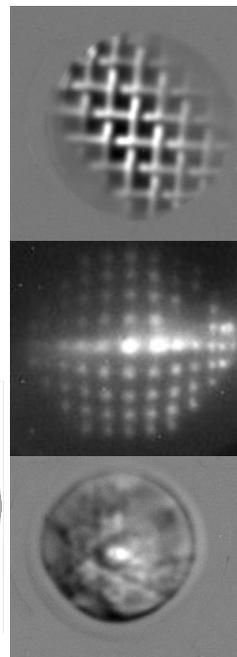
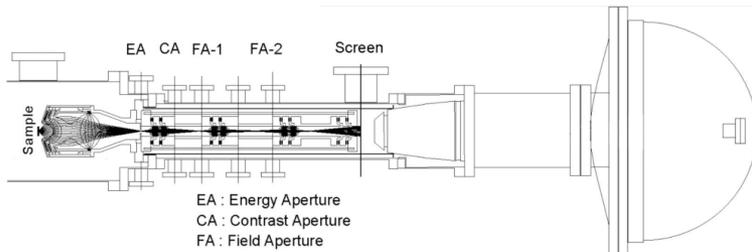
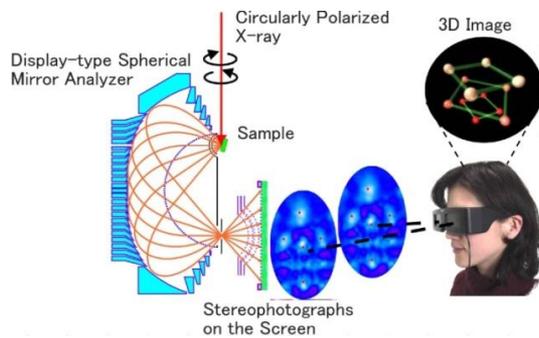
DIANA

- $\pm 60^\circ$
- $\Delta E = 0.002E_0$
- 価電子帯光電子分光
軌道解析(直線偏光)
- 内殻光電子回折
原子立体写真(円偏光)
原子層分解MCD
光電子回折分光



DELMA

- $\pm 45 \sim 60^\circ$
- $\Delta E = 0.0002E_0$
R4000で高分解能
- 価電子帯光電子分光
軌道解析 \Rightarrow 高分解能2D-ARPES
- 内殻光電子回折
原子立体写真
原子層分解MCD
光電子回折分光 \Rightarrow 化学シフト分解
- PEEM機能 ((x, y) $\Delta 30 \mu\text{m}$)
拡大像、微小試料
- HAXPES機能(深さ(z)分解 Δnm)
CrK α 6.4keV、界面組成・電子状態
- 時間分解 (in future)
2D情報が一度に
レンズシステムがTOF tube



1 D, 2D, 3D photoelectron spectroscopy

		電子状態	原子構造
		UPS $h\nu = 7 - 100 \text{ eV}$	XPS $h\nu > 100 \text{ eV}$
1D:角度積分		状態密度 $1D(E_B)$	化学シフト $1D(R)$
		$E_k = h\nu - E_B - \Phi$	
2D:角度分解		バンド分散 $2D(k, E_B)$ $3D(k_x, k_y, (E_B, k_z))$	光電子回折・ ホログラフィー 立体原子写真 $3D(x, y, z)$
3D: 空間・ 時間 分解	2D:PEEM	$nano\Delta x, y + t$ $3D(k_x, k_y, (E_B, k_z))$	
	3D:DELMA Stereo-PEEM	$micro\Delta x, y + z + t, \quad 3D(k_x, k_y, E_B), \quad 3D(x, y, z)$	